

TABLE OF CONTENTS

SECTION 1	465 SPECIFICATIONS	Page
	Introduction	1-1
	Vertical Deflection System	1-1
	Triggering	1-1
	Horizontal Deflection System	1-2
	X-Y Operation	1-3
	Calibrator	1-3
	Z Axis Input	1-3
	Signal Outputs	1-3
	Power Source	1-3
	Cathode-Ray Tube	1-3
	Supplemental Information	
	General	1-3
	Vertical Deflection System	1-3
	Triggering	1-4
	Horizontal Deflection System	1-4
	Calibrator	1-4
	External Z Axis Input	1-4
	Output Signals	1-4
	Cathode-Ray Tube	1-4
SECTION 2	OPERATING INFORMATION	
	Introduction	2-1
	Instrument Repackaging	2-1
	Operating Voltage	2-1
	Controls And Connectors	
	General	2-2
	Cathode-Ray Tube (CRT) and Display	2-2
	Vertical Deflection System	2-2
	A and B Triggering	2-4
	A and B Sweep	2-5
	Calibrator and Power	2-6
	Rear Panel	2-6
	Obtaining Basic Displays	
	Introduction	2-6
	Normal Sweep Display	2-6
	Magnified Sweep Display	2-7
	Delayed Sweep Display	2-7
	Mixed Sweep Display	2-7
	X-Y Display	2-7
SECTION 3	CIRCUIT DESCRIPTION	
	Introduction	3-1
	Digital Logic	3-1
	Block Diagram	
	General	3-1
	Channel 1 Preamp	
	General	3-3
	Input Coupling	3-3
	Input Attenuator	3-4
	Scale-Factor Switching Circuit	3-4
	Source Follower Stage	3-4
	First Cascode Amplifier Stage	3-4
	Second Cascode Amplifier Stage	3-4
	Third Cascode Amplifier Stage	3-5
	Channel 2 Preamp	
	General	3-5
	Second Cascode Amplifier	3-5
	Third Cascode Amplifier	3-6

TABLE OF CONTENTS (cont)

SECTION 3	CIRCUIT DESCRIPTION (cont)	Page
	Vertical Switching Circuit	
	General	3-6
	Diode Gates	3-6
	Switching Multivibrator	3-7
	Delay-Line Driver	3-8
	Reference Feedback Amplifier	3-8
	Normal Trigger Pickoff Amplifier	3-8
	Vertical Output Amplifier	
	General	3-8
	Delay Line	3-9
	Output Amplifier	3-9
	A and B Trigger Generators	
	General	3-9
	Trigger Source	3-9
	Trigger Coupling	3-9
	Input Source Follower	3-9
	Paraphase Amplifier	3-9
	Tunnel Diode Driver	3-10
	A And B Sweep Generators	
	General	3-10
	Disconnect Amplifier	3-10
	Sawtooth Sweep Generator	3-11
	Output Buffer Amplifier	3-11
	Sweep Start Amplifier	3-11
	Logic Multivibrator	3-11
	B Sweep Generator Differences	3-11
	Sweep And Z Axis Logic Circuit	
	General	3-11
	A Sweep Gate	3-11
	B Sweep Gate	3-12
	Sweep Control Integrated Circuit	3-12
	A Sweep Holdoff Amplifier	3-13
	B Sweep Holdoff Amplifier	3-13
	A Sweep Z-Axis Gate	3-13
	B Sweep Z-Axis Gate	3-13
	+A GATE And +B GATE Emitter Followers	3-13
	B Sweep Latch	3-14
	Horizontal Amplifier	
	General	3-14
	X-Axis Amplifier	3-14
	Input Paraphase Amplifier	3-15
	Gain Setting Amplifier	3-15
	Output Amplifier	3-15
	CRT Circuit	
	General	3-15
	High-Voltage Oscillator	3-16
	High-Voltage Regulator	3-16
	High-Voltage Rectifiers and Output	3-17
	CRT Control Circuits	3-17
	Z-Axis Amplifier	3-17
	DC Restorer Circuit	3-17
	Calibrator	
	General	3-18
	Multivibrator	3-18
	Output Amplifier	3-18
	A Trigger View Amplifier	
	General	3-18
	Amplifier	3-18

TABLE OF CONTENTS (cont)

SECTION 3	CIRCUIT DESCRIPTION (cont)	Page
	Low-Voltage Power Supply	
	General	3-19
	Power Input	3-20
	Secondary Circuit	3-20
	Fan Motor Circuit	
	General	3-20
SECTION 4	MAINTENANCE	
	Cabinet Removal	4-1
	Preventive Maintenance	
	General	4-1
	Cleaning	4-1
	Lubrication	4-2
	Transistors Checks	4-2
	Recalibration	4-2
	Corrective Maintenance	
	General	4-2
	Obtaining Replacement Parts	4-2
	Soldering Techniques	4-3
	Component Replacement	4-3
	Recalibration After Repair	4-5
	Instrument Repackaging	4-6
SECTION 5	CALIBRATION	
	Calibration Interval	5-1
	TEKTRONIX Field Service	5-1
	Using This Procedure	5-1
	Test Equipment Required	5-1
	Performance Check	
	Vertical System Check	5-6
	Trigger System Check	5-11
	Horizontal System Check	5-13
	Short-Form Calibration	
	Power Supplies And Display	5-16
	Vertical System	5-17
	Trigger System	5-19
	Horizontal System	5-21
	Detailed Calibration	
	Power Supply	5-27
	Display & Z-Axis	5-28
	Vertical System	5-30
	Trigger System	5-43
	Horizontal System	5-53
	Calibrator, Gates, & Ext Z-Axis	5-60
SECTION 6	ELECTRICAL PARTS LIST	
SECTION 7	DIAGRAMS & CIRCUIT BOARD ILLUSTRATIONS	
SECTION 8	MECHANICAL PARTS LIST & ILLUSTRATIONS	
CHANGE INFORMATION		

465 SPECIFICATIONS

Introduction

The 465 Oscilloscope is a wide-band, portable oscilloscope designed to operate in a wide range of environmental conditions. The instrument is light in weight and compact of design for ease of transportation, yet capable of performance necessary for accurate high-frequency measurements. The dual-channel, DC-to-100 megahertz vertical deflection system provides calibrated deflection factors from 5 millivolts to 5 volts/division. The bandwidth limiting switch reduces interference from signals above about 20 megahertz for viewing low-frequency, low-level signals.

The trigger circuits provide stable sweep triggering to beyond the bandwidth of the vertical deflection system. Separate controls are provided to select the desired mode of triggering for the A and B sweeps. The A sweep can be operated in one of three modes: automatic triggering, normal triggering, or single sweep. A variable trigger holdoff control provides the ability for A sweep to trigger stably on aperiodic signals or complex digital words. The horizontal deflection system has calibrated sweep rates from 0.5

second to 0.05 microsecond/division. A X10 magnifier increases each sweep rate by a factor of 10 to provide a maximum sweep rate of 5 nanoseconds/division in the 0.05 μ s position. The delayed and mixed sweep features allow the start of the B sweep to be delayed a selected amount from the start of A sweep to provide accurate relative-time measurements. Calibrated X-Y measurements can be made with Channel 2 providing the vertical deflection and Channel 1 providing the horizontal deflection (TIME/DIV switch fully counterclockwise and VERT MODE switch to CH 2). The regulated DC power supplies ensure that instrument performance is not affected by variations in line voltage and frequency. Maximum power consumption of the instrument is approximately 75 watts.

The following instrument specifications apply over an ambient temperature range of -15°C to $+55^{\circ}\text{C}$ unless otherwise specified. Warm-up time for specified accuracies is 20 minutes. The calibration procedure given in section 5, if performed completely, will allow an instrument to meet the electrical characteristics listed below.

VERTICAL DEFLECTION SYSTEM

Deflection Factor

Calibrated range is from 5 millivolts to 5 volts per division in 10 steps in a 1-2-5 sequence. Accuracy is within 3%. Uncalibrated VAR control provides deflection factors continuously variable between the calibrated settings, and extends deflection factor to at least 12.5 volts per division in the 5 volts/div position.

Frequency Response

Bandwidth in both Channel 1 and Channel 2 is DC to at least 100 megahertz. Risettime is 3.5 nanoseconds or less. The AC-coupled lower -3 dB point is 10 hertz or less (1 hertz or less when using a 10X probe). Vertical system bandwidth with the BW LIMIT pushbutton pulled is approximately 20 megahertz.

Chopped Mode Repetition Rate

Approximately 250 kilohertz.

Input Resistance And Capacitance

One megohm within 2% paralleled by approximately 20 picofarads.

Maximum Input Voltage

DC coupled: 250 V (DC + Peak AC) or 500 V P-P AC at 1 kHz or less.

AC coupled: 500 V (DC + Peak AC) or 500 V P-P AC at 1 kHz or less.

Cascaded Operation (CH 1 VERT SIGNAL OUT Connected to CH 2 OR Y)

Bandwidth is DC to at least 50 MHz with a sensitivity of at least 1 mV/division.

TRIGGERING

Sensitivity

DC Coupled: 0.3 division internal or 50 millivolts external from DC to 25 megahertz, increasing to 1.5 divisions internal or 150 millivolts external at 100 megahertz.

AC Coupled: 0.3 division internal or 50 millivolts external from 60 hertz to 25 megahertz, increasing to 1.5 divisions internal or 150 millivolts external at 100 megahertz. Attenuates all signals below about 60 hertz.

Specifications—465

LF REJ Coupled: 0.3 division internal or 100 millivolts external from 50 kilohertz to 25 megahertz, increasing to 1.5 divisions internal or 300 millivolts external at 100 megahertz. Blocks DC and attenuates all signals below about 50 kilohertz.

HF REJ Coupled: 0.3 division internal or 50 millivolts external from 60 hertz to 50 kilohertz. Blocks DC and attenuates all signals below about 60 hertz and above about 50 kilohertz.

Trigger Jitter

0.5 nanosecond or less at 5 nanoseconds/division with 100 megahertz applied (X10 MAG on).

External Trigger Input

Maximum input voltage is 250 V DC + peak AC or 250 V P-P AC (1 kilohertz or less). Input resistance is 1 megohm within 10%.

LEVEL Control Range

EXT: At least + and – 2 volts, 4 volts peak to peak.

EXT ÷10: At least + and – 20 volts, 40 volts peak to peak.

HORIZONTAL DEFLECTION SYSTEM

Calibrated Sweep Range

A Sweep: from 0.5 second/division to 0.05 microsecond/division in 22 steps in a 1-2-5 sequence. X10 MAG extends maximum sweep rate to 5 nanoseconds/division.

B Sweep: from 50 milliseconds/division to 0.05 microsecond/division in 19 steps in a 1-2-5 sequence. X10 MAG extends maximum sweep rate to 5 nanoseconds/division.

Calibrated Sweep Accuracy

Unmagnified sweep accuracy is $\pm 2\%$ from $+20^{\circ}\text{C}$ to $+30^{\circ}\text{C}$ ($+68^{\circ}\text{F}$ to $+86^{\circ}\text{F}$) and $\pm 3\%$ from -15°C to $+20^{\circ}\text{C}$ and $+30^{\circ}\text{C}$ to $+55^{\circ}\text{C}$ ($+5^{\circ}\text{F}$ to $+68^{\circ}\text{F}$ and $+86^{\circ}\text{F}$ to $+131^{\circ}\text{F}$). For the same temperature ranges, magnified sweep accuracy is $\pm 3\%$ and $\pm 4\%$ respectively. Exclude the first and last 50 ns of the 5 ns, 10 ns, and 20 ns magnified sweep rates. Accuracy specifications apply over full ten divisions unless otherwise specified.

Sweep accuracy, over any two or less division portion of the sweep, is $\pm 5\%$. Exclude the first and last magnified divisions of the 5 ns and 10 ns/div magnified sweep rates. Also exclude the first and last 50 ns of the 5, 10, and 20 ns/div magnified sweep rates.

Mixed sweep accuracy is 2% plus the measured A sweep error when viewing the A sweep portion only. The B sweep portion retains its normal accuracy.

A Time/Division Variable Range

Provides continuously variable (uncalibrated) sweep rates between the calibrated settings of the A TIME/DIV switch. Extends the slowest A sweep rate to at least 1.25 seconds/division.

A Trigger Holdoff

Increases A sweep holdoff time by at least a factor of 10.

Delay Time And Differential Time Measurement Accuracy

	$+15^{\circ}\text{C}$ to $+35^{\circ}\text{C}$ ($+60^{\circ}\text{F}$ to $+95^{\circ}\text{F}$)	-15°C to $+55^{\circ}\text{C}$ ($+5^{\circ}\text{F}$ to $+131^{\circ}\text{F}$)
Over One Or More Major Dial Division	$\pm 1\%$	$\pm 2.5\%$
Over Less Than One Major Dial Division	± 0.01 Major Dial Division	± 0.03 Major Dial Division

Delay Time Jitter

Within 0.002% (less than one part in 50,000) of the maximum available delay time when operating on power line frequencies other than 50 Hz.

Within 0.005% (less than one part in 20,000) of the maximum available delay time when operating on 50 Hz power line frequency.

Maximum available delay time is ten times the setting of the A TIME/DIV switch.

Calibrated Delay Time (A VAR set to calibrated position)

Continuous from 5 seconds to 0.2 microsecond.

b. Adjust the CH 1 POSITION control for a 0 volt reading on the meter.

c. ADJUST—Vertical Output Centering adjustment, R429, (see Fig. 5-9) to position the trace to the center graticule line.

d. Remove the DC Voltmeter lead connections.

e. Position the trace off-screen with the CH 1 POSITION and horizontal POSITION controls.

f. Push the BEAM FIND button and hold it in.

g. CHECK—That the trace is brought into the CRT viewing area.

h. Release the BEAM FIND button.

11. Adjust CH 1 Step Attenuator Balance

a. Set the CH 1 VOLTS/DIV switch to 20 mV and the CH 1 INPUT COUPLING switch to GND.

b. Position the trace to the center horizontal graticule line.

c. CHECK—CRT display for 0.2 division or less of trace shift between adjacent switch positions when rotating the CH 1 VOLTS/DIV switch from 20 mV to 5 mV.

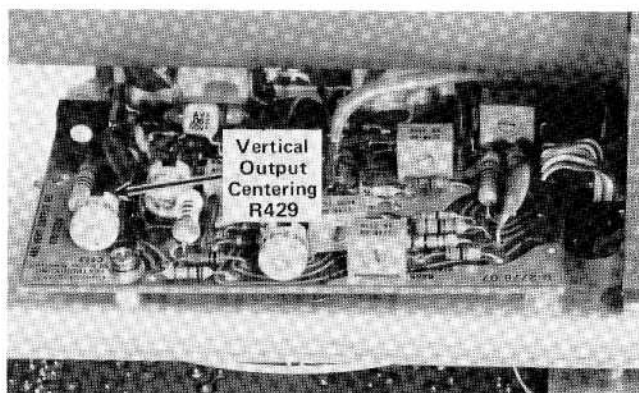


Fig. 5-9. Location of Vertical Output Centering adjustment.

d. ADJUST—CH 1 Step Atten Bal adjustment, R25, (see Fig. 5-10) for minimum trace shift when rotating the CH 1 VOLTS/DIV switch from 20 mV to 5 mV.

12. Adjust CH 1 Variable Volts/Division Balance

a. Position the trace to the center horizontal graticule line.

b. CHECK—That the CH 1 UNCAL light comes on when the VAR control is out of the detent position.

c. CHECK—CRT display for 1.0 division or less of trace shift when rotating the CH 1 VAR control through its range.

d. ADJUST—CH 1 Variable Balance adjustment, R120, (see Fig. 5-11) for minimum trace shift when rotating the CH 1 VAR control through its range.

e. Return the CH 1 VAR control to the detent position.

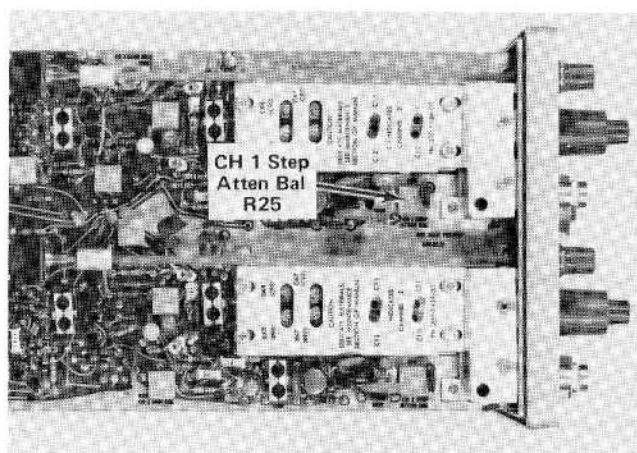


Fig. 5-10. Location of CH 1 Step Atten Bal adjustment.

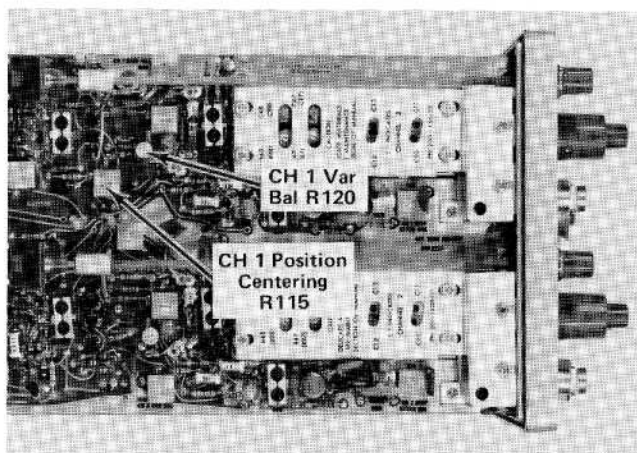
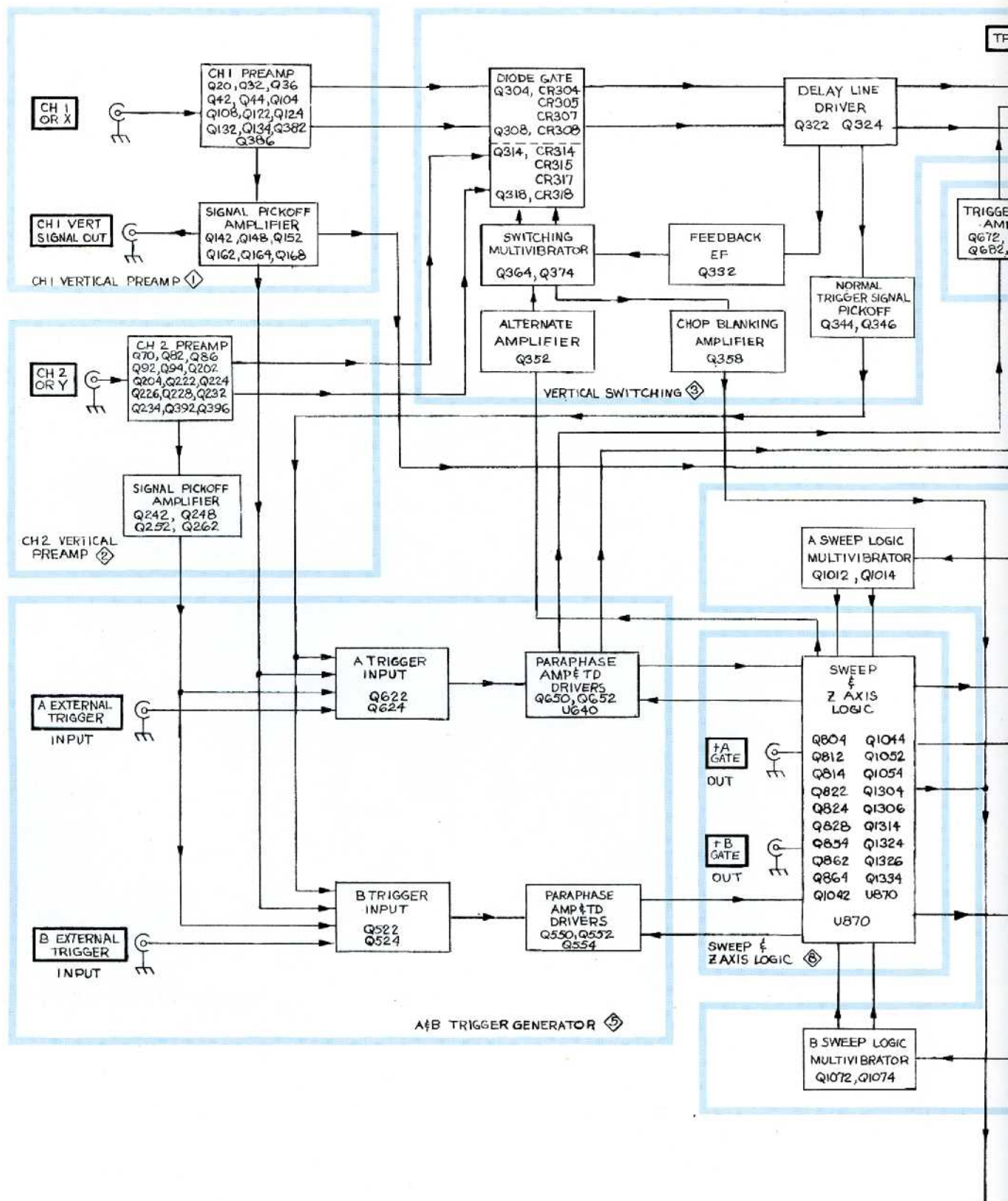
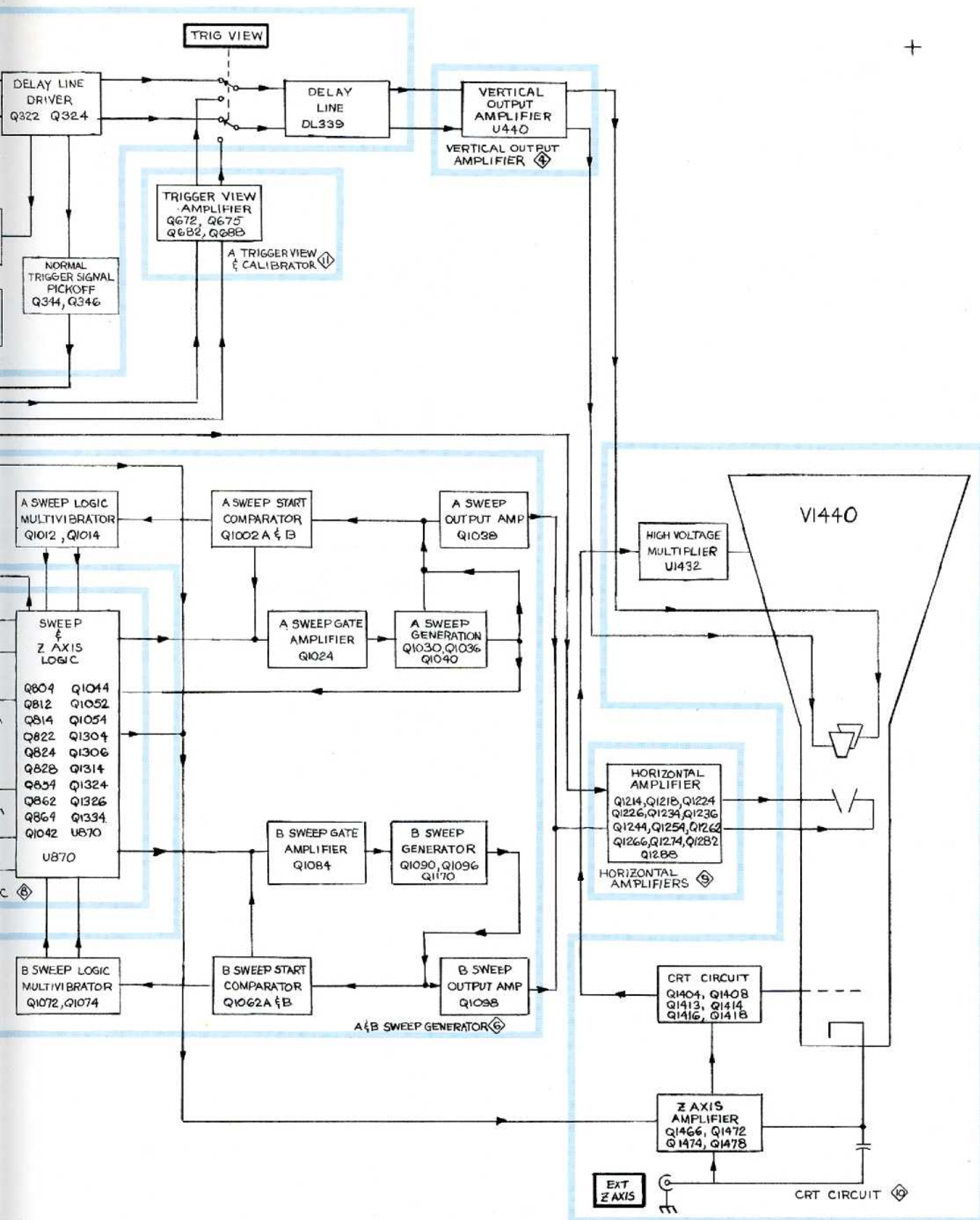


Fig. 5-11. Location of CH 1 Variable Balance and Position Centering adjustment.

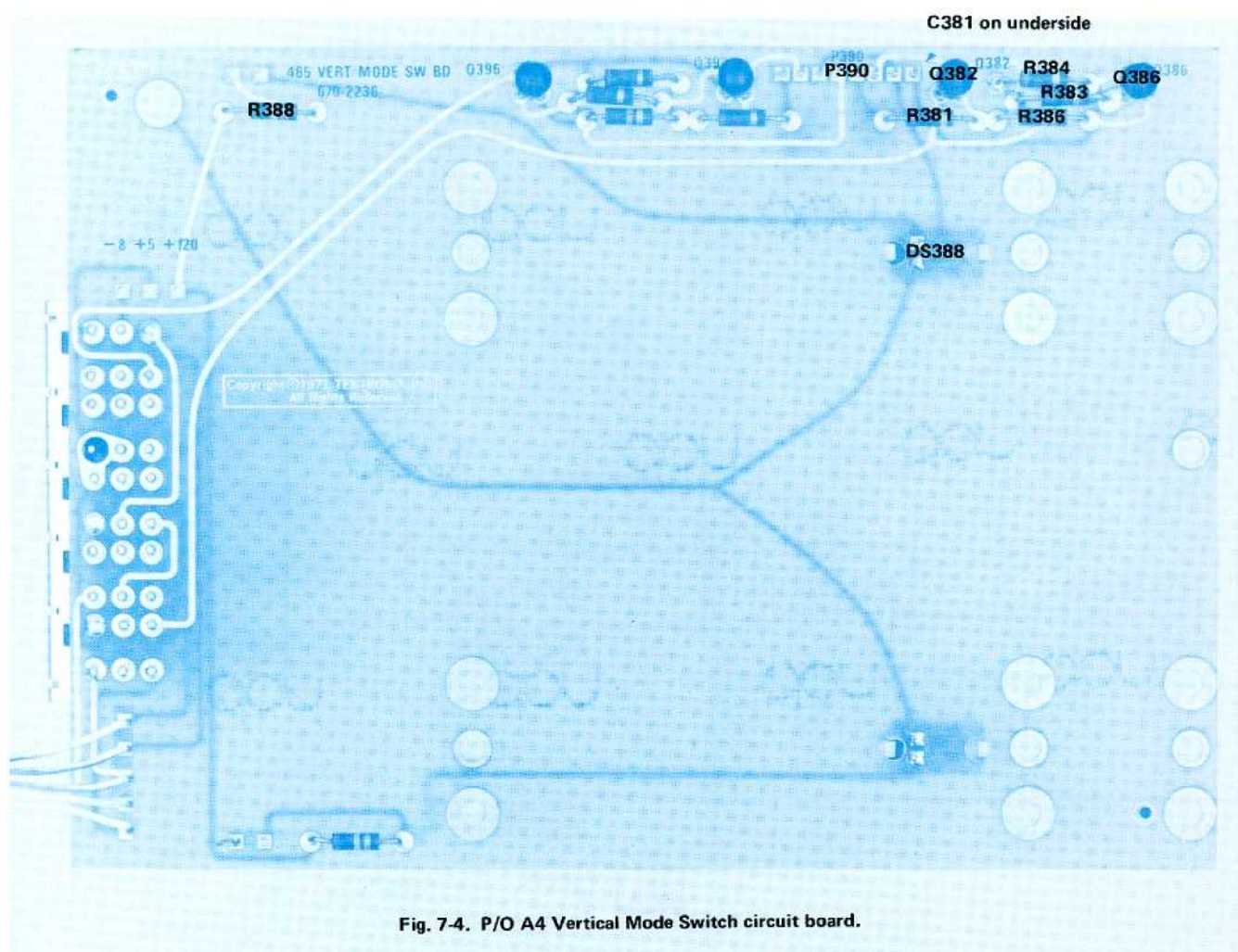
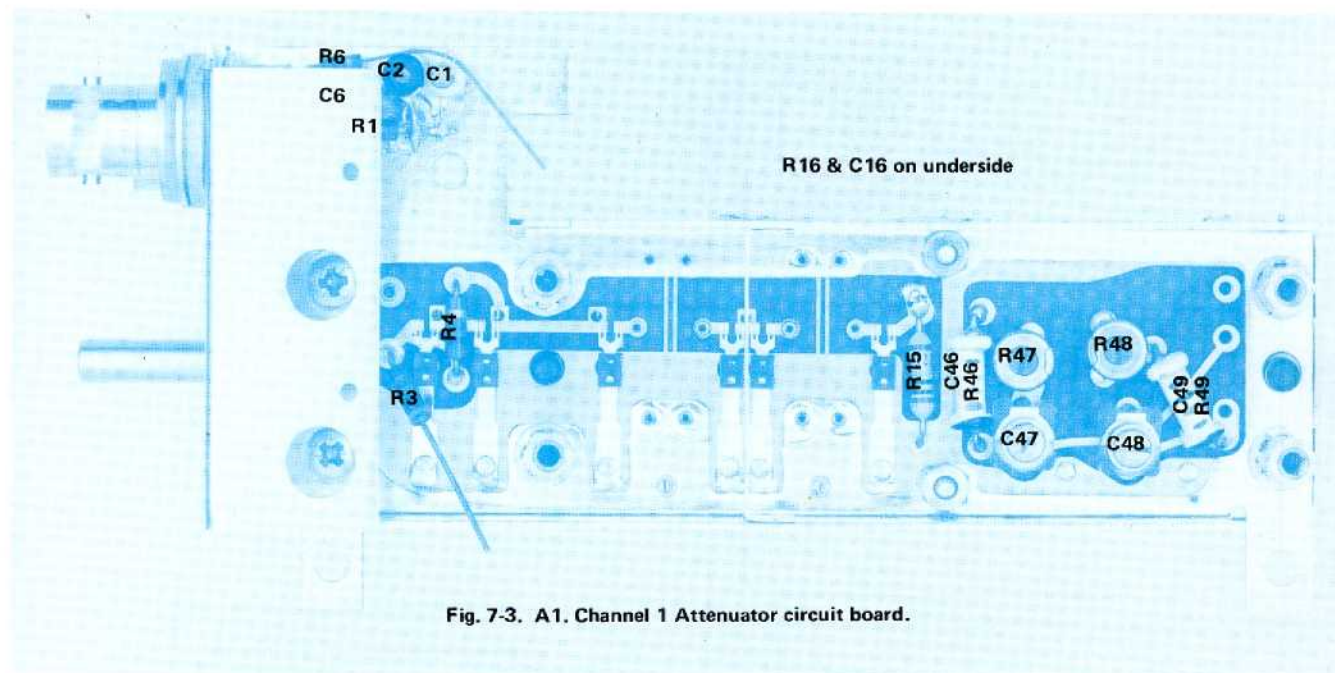
Ckt. No.	Tektronix Part No.	Serial/Model No. Eff	No. Disc	Description
DIODES (cont)				
CR825	152-0141-02			Silicon, 1N4152
CR826	152-0141-02			Silicon, 1N4152
CR831	152-0141-02			Silicon, 1N4152
CR832	152-0141-02			Silicon, 1N4152
CR838	152-0141-02			Silicon, 1N4152
CR851	152-0322-00			Silicon, All08
CR859	152-0141-02			Silicon, 1N4152
CR863	152-0141-02	XB010600		Silicon, 1N4152
CR879	152-0141-02			Silicon, 1N4152
CR1001	152-0141-02			Silicon, 1N4152
CR1004	152-0141-02			Silicon, 1N4152
CR1011	152-0141-02			Silicon, 1N4152
CR1024	152-0141-02			Silicon, 1N4152
CR1035	152-0141-02			Silicon, 1N4152
CR1042	152-0141-02			Silicon, 1N4152
CR1043	152-0141-02			Silicon, 1N4152
CR1061	152-0141-02			Silicon, 1N4152
CR1064	152-0141-02			Silicon, 1N4152
CR1071	152-0141-02			Silicon, 1N4152
CR1095	152-0141-02			Silicon, 1N4152
CR1101	152-0141-02			Silicon, 1N4152
CR1102	152-0141-02			Silicon, 1N4152
CR1155	152-0333-00			Silicon, FDH6012
CR1201	152-0141-02			Silicon, 1N4152
CR1202	152-0141-02			Silicon, 1N4152
CR1216	152-0141-02			Silicon, 1N4152
CR1248	152-0141-02			Silicon, 1N4152
CR1251	152-0153-00			Silicon, FD7003 or CD5574
CR1252	152-0153-00			Silicon, FD7003 or CD5574
CR1253	152-0322-00			Silicon, All08
CR1255	152-0141-02			Silicon, 1N4152
CR1273	152-0322-00			Silicon, All08
CR1275	152-0141-02			Silicon, 1N4152
CR1286	152-0141-02			Silicon, 1N4152
CR1304	152-0141-02			Silicon, 1N4152
CR1306	152-0141-02			Silicon, 1N4152
CR1309	152-0141-02			Silicon, 1N4152
CR1315	152-0141-02			Silicon, 1N4152
CR1316	152-0141-02			Silicon, 1N4152
CR1325	152-0141-02			Silicon, 1N4152
CR1326	152-0141-02			Silicon, 1N4152
CR1327	152-0141-02			Silicon, 1N4152
CR1334	152-0141-02			Silicon, 1N4152
CR1335	152-0141-02			Silicon, 1N4152
CR1336	152-0141-02			Silicon, 1N4152

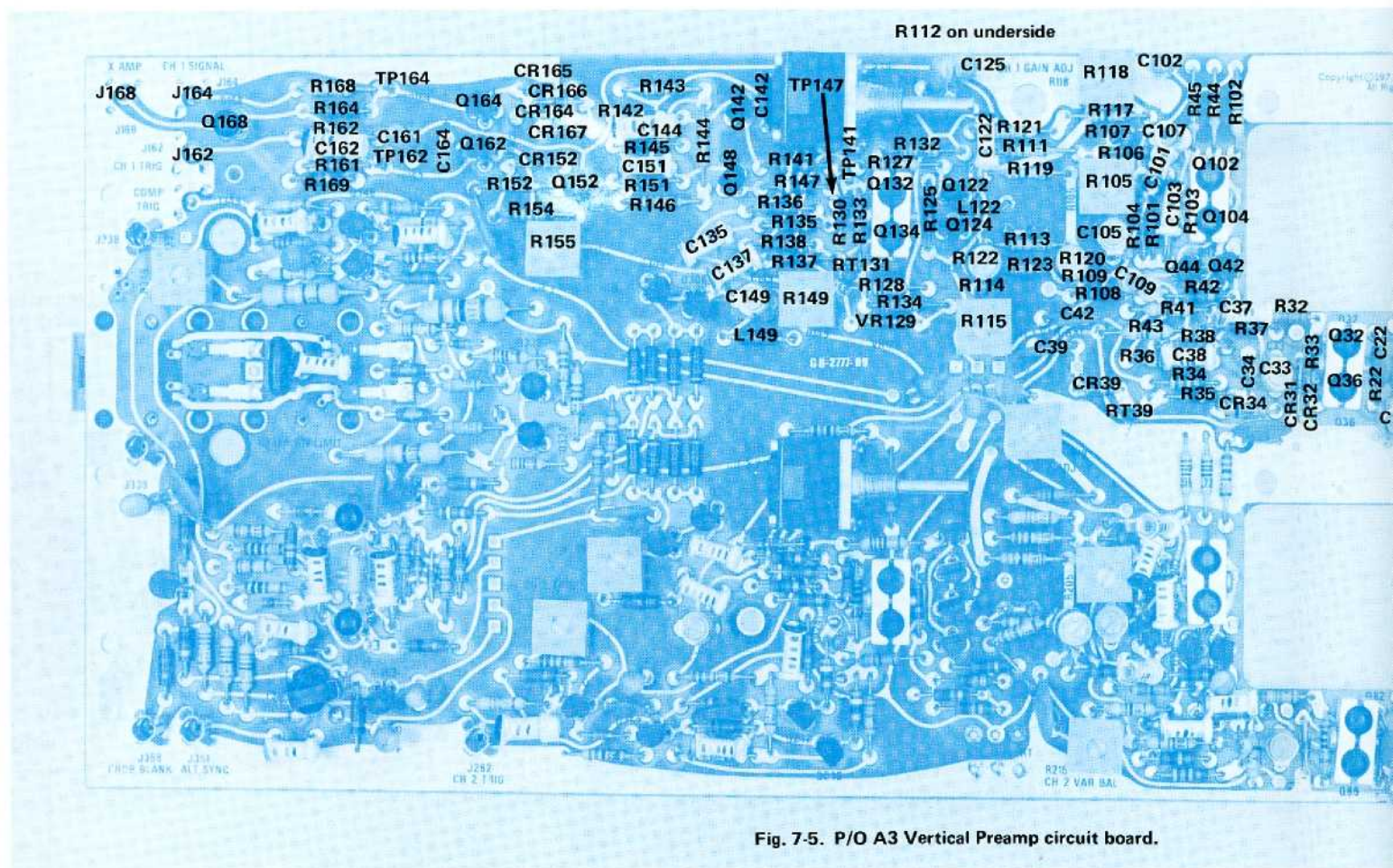




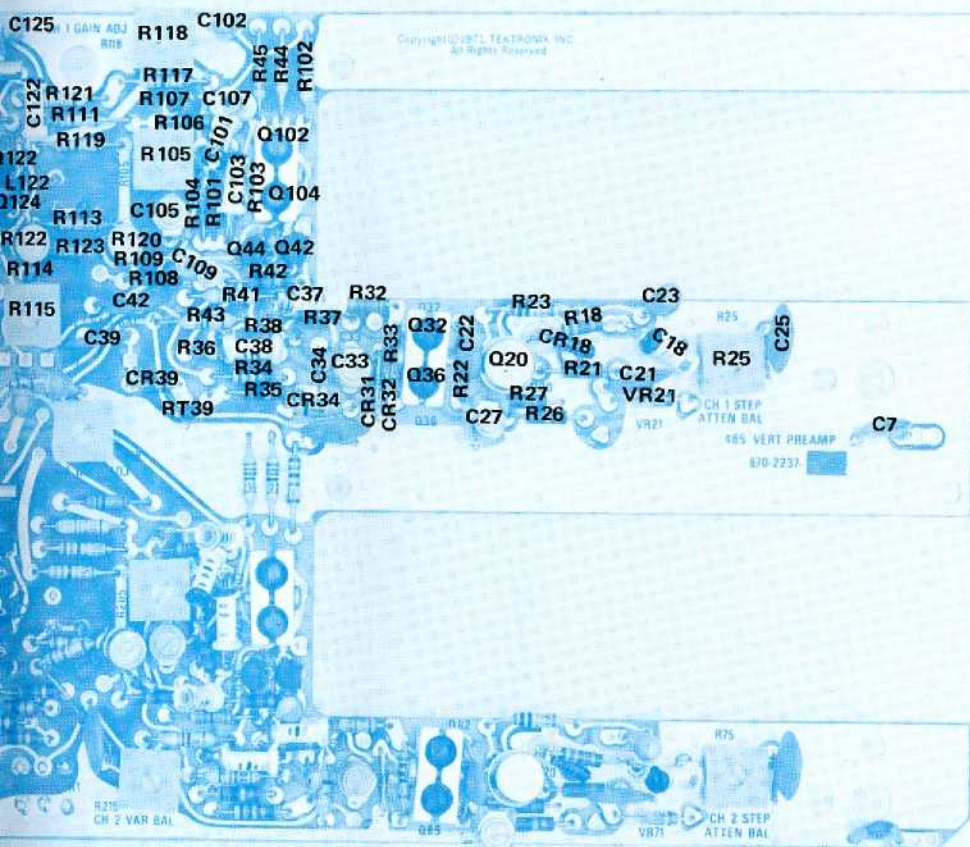
BLOCK DIAGRAM

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on underside



al Preamp circuit board.

- c. Adjust the A LEVEL control for a stable display.
- d. Position the top of the display to the bottom graticule line.
- e. CHECK - CRT display for less than 5% aberrations.
- f. Set the Pulse Generator polarity to - and the 465 A SLOPE switch to -.
- g. Position the bottom of the display to the top graticule line.
- h. CHECK - CRT display for less than 7% aberrations.

31. Adjust CH 1 High-Frequency Compensation

- a. Move the test signal from CH 2 to the CH 1 input.
- b. Set the A TIME/DIV switch to 0.05 μ s, the A SLOPE switch to +, and the VERT MODE switch to CH 1.
- c. Set the Fast-Rise High-Amplitude Pulse Generator (Type 109) to + and adjust the Pulse Generator for five divisions of deflection. Remove or add attenuators as necessary to maintain a five division display throughout this step.
- d. CHECK - CRT display for risetime of 3.5 nanoseconds or less.
- e. CHECK - CRT display for flat-top waveform with 3% or less of aberrations.
- f. ADJUST - C27, C33, C105, R105, R122, C122, C149, and R149 (see Fig. 5-23) with a low-capacitance screwdriver, for the best flat-top waveform.
- g. Set the Pulse Generator polarity to - and the 465 A SLOPE switch to -.

TABLE OF CONTENTS

	Page
LIST OF ILLUSTRATIONS	v
LIST OF TABLES	v
SECTION 1 SPECIFICATIONS	
Introduction	1-1
VERTICAL DEFLECTION SYSTEM	1-1
TRIGGERING	1-1
HORIZONTAL DEFLECTION SYSTEM	1-2
X-Y OPERATION	1-2
CALIBRATOR	1-3
Z-AXIS INPUT	1-3
SIGNAL OUTPUTS	1-3
POWER SOURCE	1-3
CATHODE RAY TUBE (CRT)	1-3
SUPPLEMENTAL INFORMATION	1-3
Vertical Deflection System	1-3
Triggering	1-4
Horizontal Deflection System	1-4
Calibrator	1-4
External Z-Axis Input	1-4
Output Resistances	1-4
Cathode Ray Tube (CRT)	1-4
SECTION 2 OPERATING INFORMATION	
Introduction	2-1
Instrument Repackaging	2-1
Operating Voltage	2-1
CONTROLS AND CONNECTORS	2-2
Introduction	2-2
Cathode Ray Tube (CRT) and Display	2-2
Vertical Deflection System	
Channel 1 and Channel 2	2-2
A and B Triggering	2-4
A and B Sweep	2-5
Calibrator and Power	2-6
Rear Panel	2-6
OBTAINING BASIC DISPLAYS	2-6
Introduction	2-6
Normal Sweep Display	2-6
Magnified Sweep Display	2-7
Delayed Sweep Display	2-7
Mixed Sweep Display	2-7
X-Y Display	2-7

TABLE OF CONTENTS (cont)

SECTION 3	CIRCUIT DESCRIPTION	Page
	Introduction	3-1
	Digital Logic	3-1
	BLOCK DIAGRAM	3-1
	CHANNEL 1 PREAMP	3-3
	Introduction	3-3
	Scale Factor Switching	3-4
	Input Coupling	3-4
	Input Attenuator	3-4
	Source Follower	3-4
	First Cascode Amplifier	3-5
	Second Cascode Amplifier	3-5
	Third Cascode Amplifier	3-5
	CHANNEL 2 PREAMP	3-5
	Introduction	3-5
	Second Cascode Amplifier	3-5
	Third Cascode Amplifier	3-6
	VERTICAL SWITCHING CIRCUIT	3-6
	Introduction	3-6
	Diode Gates	3-6
	Switching Multivibrator	3-7
	Delay Line Driver	3-9
	Reference Feedback Amplifier	3-9
	Normal Trigger Pickoff	3-9
	VERTICAL OUTPUT AMPLIFIER	3-9
	Introduction	3-9
	Delay Line	3-9
	Vertical Output Amplifier—Discrete Version	3-9
	Vertical Output Amplifier—IC Version	3-10
	A AND B TRIGGER GENERATORS	3-10
	Introduction	3-10
	Trigger Source	3-10
	Trigger Coupling	3-10
	Input Source Follower	3-10
	Paraphase Amplifier	3-10
	Tunnel Diode Driver	3-11
	A AND B SWEEP GENERATOR	3-11
	Introduction	3-11
	Disconnect Amplifier	3-12
	Output Buffer Amplifier	3-12
	Sweep Start Amplifier	3-12
	Logic Multivibrator	3-12
	B Sweep Differences	3-12
	SWEEP AND Z-AXIS LOGIC CIRCUIT	3-13
	Introduction	3-13
	A Sweep Gate	3-13

TABLE OF CONTENTS (cont)

	Page
SECTION 3 (cont)	
B Sweep Gate	3-13
Sweep Control Integrated Circuit	3-13
Holdoff Timing	3-14
A Sweep Holdoff Amplifier	3-14
B Sweep Holdoff Amplifier	3-14
B Sweep Latch	3-14
A Sweep Z Axis Gate	3-14
B Sweep Z Axis	3-15
A +Gate and B +Gate Emitter Followers	3-15
HORIZONTAL AMPLIFIER	3-15
Introduction	3-15
X-Axis Amplifier	3-15
Input Paraphase Amplifier	3-16
Gain Setting Amplifier	3-16
Output Amplifier	3-16
CRT CIRCUIT	3-17
Introduction	3-17
High Voltage Oscillator	3-17
High Voltage Regulator	3-18
High Voltage Rectifier and Output	3-18
CRT Control Circuits	3-18
Z Axis Amplifier	3-18
DC Restorer Circuit	3-19
CALIBRATOR	3-19
Introduction	3-19
Multivibrator	3-19
Output Amplifier	3-19
A TRIGGER VIEW AMPLIFIER	3-20
Introduction	3-20
Amplifier	3-20
LOW VOLTAGE POWER SUPPLY	3-20
Introduction	3-20
Power Input	3-20
Secondary Circuit	3-20
FAN MOTOR CIRCUIT	3-22
 SECTION 4	
 MAINTENANCE	
Introduction	4-1
Cabinet Removal	4-1
 PREVENTIVE MAINTENANCE	4-1
Introduction	4-1
Cleaning	4-1
Visual Inspection	4-2
Lubrication	4-3
Semiconductor Checks	4-3
Recalibration	4-3

TABLE OF CONTENTS (cont)

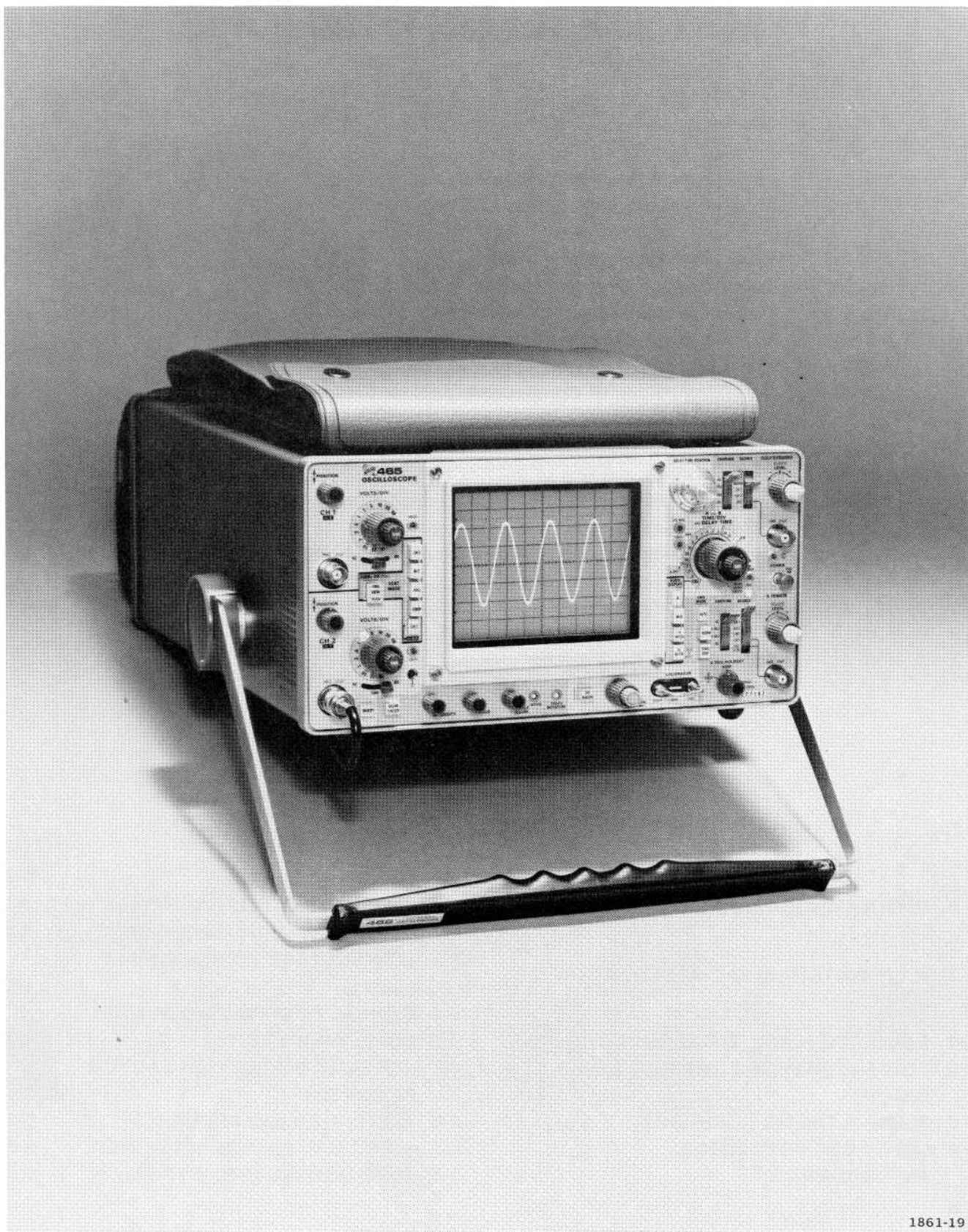
	Page
SECTION 4 (cont) TROUBLESHOOTING	4-3
Introduction	4-3
Troubleshooting Aids	4-3
Troubleshooting Equipment	4-5
Troubleshooting Techniques	4-5
CORRECTIVE MAINTENANCE	4-7
Introduction	4-7
Obtaining Replacement Parts	4-7
Soldering Techniques	4-8
Component Removal and Replacement	4-9
Recalibration After Repair	4-14
Instrument Repackaging	4-14
SECTION 5 PERFORMANCE CHECK	
Purpose	5-1
Limits and Tolerances	5-1
Line Voltage Selection	5-1
Equipment Required	5-1
Special Fixtures	5-1
Test Equipment Alternatives	5-1
INDEX TO PERFORMANCE CHECK	5-1
VERTICAL	5-3
TRIGGERS	5-7
HORIZONTAL	5-10
SECTION 6 CALIBRATION	
Purpose	6-1
Limits and Tolerances	6-1
Step Titles	6-1
Line Voltage Selection	6-1
Internal Adjustments	6-1
Display	6-1
Test Equipment Required	6-1
Interactions	6-1
INDEX TO CALIBRATION PROCEDURE	6-5
POWER SUPPLY	6-8
DISPLAY AND Z-AXIS	6-10
VERTICAL	6-12
TRIGGERS	6-24
HORIZONTAL	6-35
GATES, CALIBRATOR AND EXT Z-AXIS	6-43
SECTION 7 ELECTRICAL PARTS LIST	7-1
OPTIONS	TAB PAGE
SECTION 8 DIAGRAMS	8-1
SECTION 9 MECHANICAL PARTS LIST	9-1
CHANGE INFORMATION	

LIST OF ILLUSTRATIONS

		Page
Fig. 1-1	465 Oscilloscope	
Fig. 2-1	Power supply regulating range selector.	2-2
Fig. 2-2	Front and rear panel controls and connectors.	2-2
Fig. 3-1	Basic block diagram of the 465.	3-2
Fig. 3-2	Detailed block diagram of the Channel 1 Preamplifier.	3-3
Fig. 3-3	Detailed block diagram of the Channel 2 Preamplifier.	3-6
Fig. 3-4	Detailed block diagram of the Vertical Switching Circuit.	3-7
Fig. 3-4	Effect of Diode Gates on signal path (simplified Vertical Switching diagram). Conditions shown for CH 1 position of Vertical Mode switch.	3-8
Fig. 3-6	Detailed block diagram of the A Sweep Generator.	3-11
Fig. 3-7	Detailed block diagram of the Horizontal Amplifier.	3-16
Fig. 3-8	Detailed block diagram of the CRT and Z-Axis circuits.	3-17
Fig. 3-9	Detailed block diagram of the Calibrator circuit.	3-19
Fig. 3-10	Detailed block diagram of the Trigger View Amplifier.	3-20
Fig. 3-11	Detailed block diagram of the Low Voltage Power Supply.	3-21
Fig. 3-12	Foldover circuit action.	3-22
Fig. 4-1	Removing the wrap around cabinet.	4-1
Fig. 4-2	Color codes.	4-4

LIST OF TABLES

	Page		Page
2-1 REGULATING RANGES	2-1	6-1 ADJUSTMENT INTERACTIONS	6-2
		6-2 TEST EQUIPMENT REQUIRED	6-3
3-1 GAIN SWITCHING AND ATTENUATION	3-4	6-3 LOW VOLTAGE POWER SUPPLY LIMITS	6-8
		6-4 TYPICAL LOW VOLTAGE POWER SUPPLY RIPPLE	6-9
5-1 DEFLECTION FACTOR ACCURACY	5-5	6-5 VERTICAL DEFLECTION FACTOR ACCURACY	6-16
5-2 LOW FREQUENCY COMPENSATION SETUP	5-5	6-6 A AND B TIMING ACCURACY	6-39
5-3 A AND B TIMING ACCURACY	5-10	6-7 A AND B MAGNIFIED ACCURACY	6-39
5-4 DELAY OR DIFFERENTIAL TIME ACCURACY	5-11	6-8 DIFFERENTIAL TIME ACCURACY	6-40



1861-19

Fig. 1-1. 465 Oscilloscope.

SPECIFICATIONS

Introduction

The 465 Oscilloscope is a wide-band, portable oscilloscope designed to operate in a wide range of environmental conditions. The instrument is light in weight and compact of design for ease of transportation, yet capable of performance necessary for accurate high-frequency measurements. The dual-channel dc-to-100 megahertz vertical deflection system provides calibrated deflection factors from 5 millivolts to 5 volts/division. The bandwidth limiting switch reduces interference from signals above about 20 megahertz for viewing low-frequency, low-level signals.

The trigger circuits provide stable sweep triggering to beyond the bandwidth of the vertical deflection system. Separate controls are provided to select the desired mode of triggering for the A and B sweeps. The A sweep can be operated in one of three modes: automatic triggering, normal triggering, or single sweep. A variable trigger holdoff control provides the ability for A sweep to trigger stably on aperiodic signals or complex digital words. The horizontal deflection system has calibrated sweep rates from 0.5 second to 0.05 microsecond/division. A X10 magnifier increases each sweep rate by a factor of 10 to provide a maximum sweep rate of 5 nanoseconds/division in the 0.05 μ s position. The delayed and mixed sweep features allow the start of the B sweep to be delayed a selected amount from the start of A sweep to provide accurate relative-time measurements. Calibrated X-Y measurements can be made with Channel 2 providing the vertical deflection and Channel 1 providing the horizontal deflection (TIME/DIV switch fully counterclockwise and VERT MODE switch to CH 2). The regulated dc power supplies ensure that instrument performance is not affected by variations in line voltage and frequency. Maximum power consumption of the instrument is approximately 75 watts.

The following instrument specifications apply over an ambient temperature range of -15°C to $+55^{\circ}\text{C}$ unless otherwise specified. Warm-up time for specified accuracies is 20 minutes. The calibration procedure given in section 6, if performed completely, will allow an instrument to meet the electrical characteristics listed below.

VERTICAL DEFLECTION SYSTEM

Deflection Factor

Calibrated range is from 5 millivolts to 5 volts/division in 10 steps in a 1-2-5 sequence. Accuracy is within 3%. Uncalibrated VAR control provides deflection factors continuously variable between the calibrated settings and extends deflection factor to at least 12.5 volts/division in the 5 VOLTS/DIV position.

Frequency Response

Bandwidth in both Channel 1 and Channel 2 is dc to at least 100 megahertz from -15°C to $+40^{\circ}\text{C}$ and dc to at least 85 megahertz from $+40^{\circ}\text{C}$ to $+55^{\circ}\text{C}$. Risetime is 3.5 nanoseconds or less from 0°C to $+40^{\circ}\text{C}$ and 4.2 nanoseconds or less from $+40^{\circ}\text{C}$ to $+55^{\circ}\text{C}$. The ac-coupled lower -3 dB point is 10 hertz or less (1 hertz or less when using a 10X probe). Vertical system bandwidth with the BW LIMIT pushbutton pulled is approximately 20 megahertz.

Chopped Mode Repetition Rate

Approximately 250 kilohertz.

Input Resistance And Capacitance

One megohm within 2% paralleled by approximately 20 picofarads.

Maximum Input Voltage

Dc coupled: 250 V (dc + peak ac) or 500 V p-p ac at 1 kHz or less.

Ac coupled: 500 V (dc + peak ac) or 500 V p-p ac at 1 kHz or less.

Cascaded Operation (CH 1 VERT SIGNAL OUT Connected to CH 2 OR Y)

Bandwidth is dc to at least 50 MHz with a sensitivity of at least 1 millivolt/division.

TRIGGERING

Sensitivity

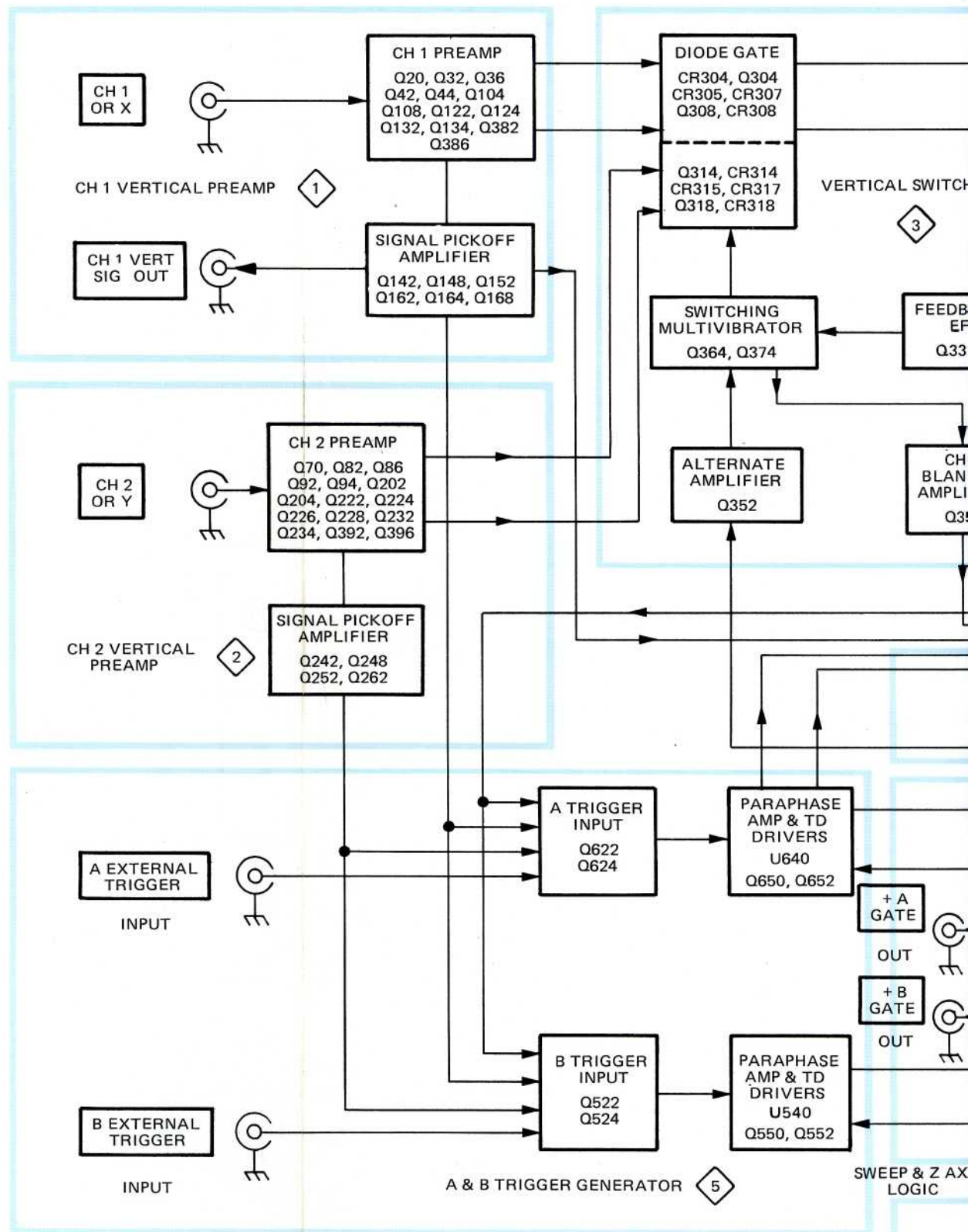
DC Coupled: 0.3 division internal or 50 millivolts external from dc to 25 megahertz, increasing to 1.5 divisions internal or 150 millivolts external at 100 megahertz.

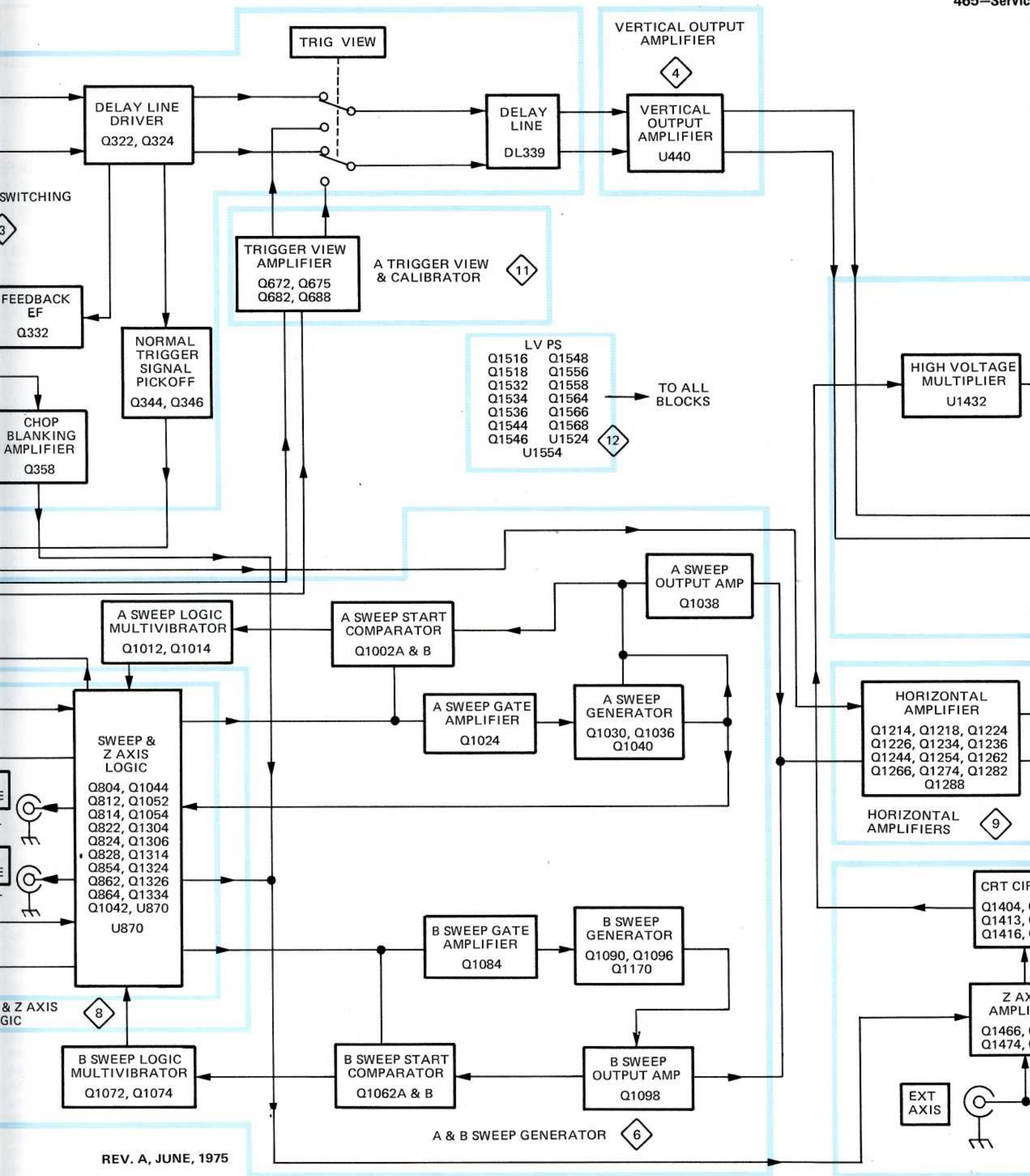
AC Coupled: 0.3 division internal or 50 millivolts external from 60 hertz to 25 megahertz, increasing to 1.5 divisions internal or 150 millivolts external at 100 megahertz. Attenuates all signals below about 60 hertz.

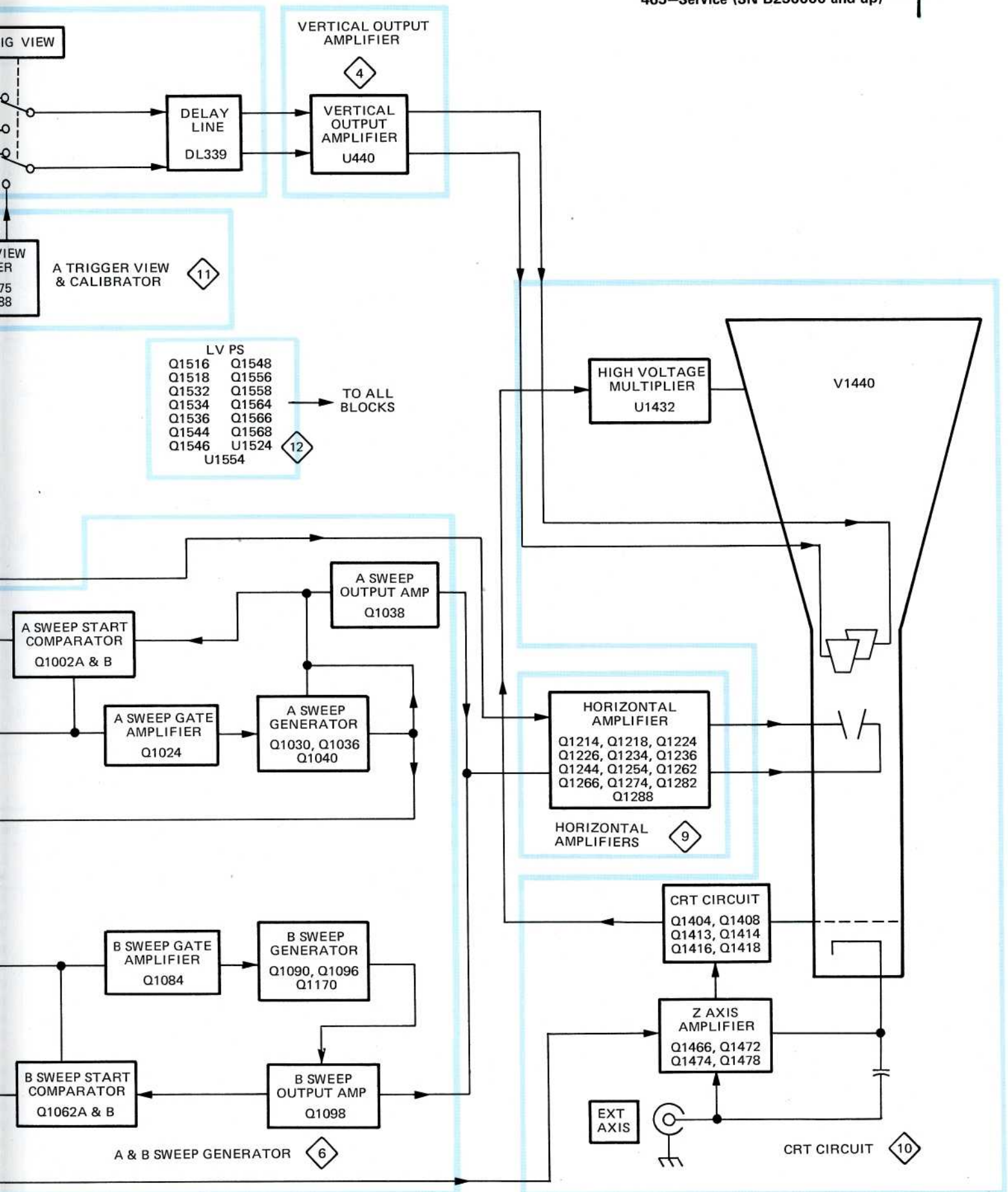
LF REJ Coupled: 0.5 division internal or 100 millivolts external from 50 kilohertz to 25 megahertz, increasing to 1.5 divisions internal or 300 millivolts external at

Electrical Parts List—465 Service (SN B250000-Up)

Ckt No.	Tektronix Part No.	Serial/Model No. Eff	Dscont	Name & Description	Mfr Code	Mfr Part Number
CR68	152-0323-00			SEMICON D DEVICE:SILICON,35V,100MA	03508	SE365
CR81	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR82	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR84	152-0271-00			SEMICON D DEVICE:SILICON,10PF	01281	V10E
CR152	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR164	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR165	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR166	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR167	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR252	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR304	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR305	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR307	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR308	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR314	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR315	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR317	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR318	152-0153-00			SEMICON D DEVICE:SILICON,15V,50MA	13715	FD7003
CR342	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR362	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR368	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR372	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR378	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR421	152-0269-00			SEMICON D DEVICE:SILICON,VAR VCAP.,4V,33PF	25403	1N3182
CR422	152-0269-00			SEMICON D DEVICE:SILICON,VAR VCAP.,4V,33PF	25403	1N3182
CR517	152-0246-00			SEMICON D DEVICE:SILICON,400PIV,200MA	07910	CD12676
CR550	152-0125-00	B250000	B256799	SEMICON D DEVICE:TUNNEL,15PF,4.7MA	03508	STD704
CR550	152-0125-01	B256800		SEMICON D DEVICE:TUNNEL,15PF,4.7MA		
CR552	152-0125-00	B256800	B256799	SEMICON D DEVICE:TUNNEL,15PF,4.7MA	03508	STD704
CR552	152-0125-01	B250000		SEMICON D DEVICE:TUNNEL15PF,4.7MA		
CR553	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR554	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR617	152-0246-00			SEMICON D DEVICE:SILICON,400PIV,200MA	07910	CD12676
CR650	152-0125-00	B250000	B256799	SEMICON D DEVICE:TUNNEL,15PF,4.7MA	03508	STD704
CR650	152-0125-01	B256800		SEMICON D DEVICE:TUNNEL,15PF,4.7MA		
CR652	152-0125-00	B250000	B257699	SEMICON D DEVICE:TUNNEL,15PF,4.7MA	03508	STD704
CR652	152-0125-01	B256800		SEMICON D DEVICE:TUNNEL,15PF,4.7MA		
CR801	152-0322-00			SEMICON D DEVICE:SILICON,15V	28480	5082-2672
CR809	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR818	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR822	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR825	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR826	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR831	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR832	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR838	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR851	152-0322-00			SEMICON D DEVICE:SILICON,15V	28480	5082-2672
CR859	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR862	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR863	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR877	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR1001	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR1004	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR1011	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR1024	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR1035	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152
CR1042	152-0141-02			SEMICON D DEVICE:SILICON,30V,150MA	07910	1N4152

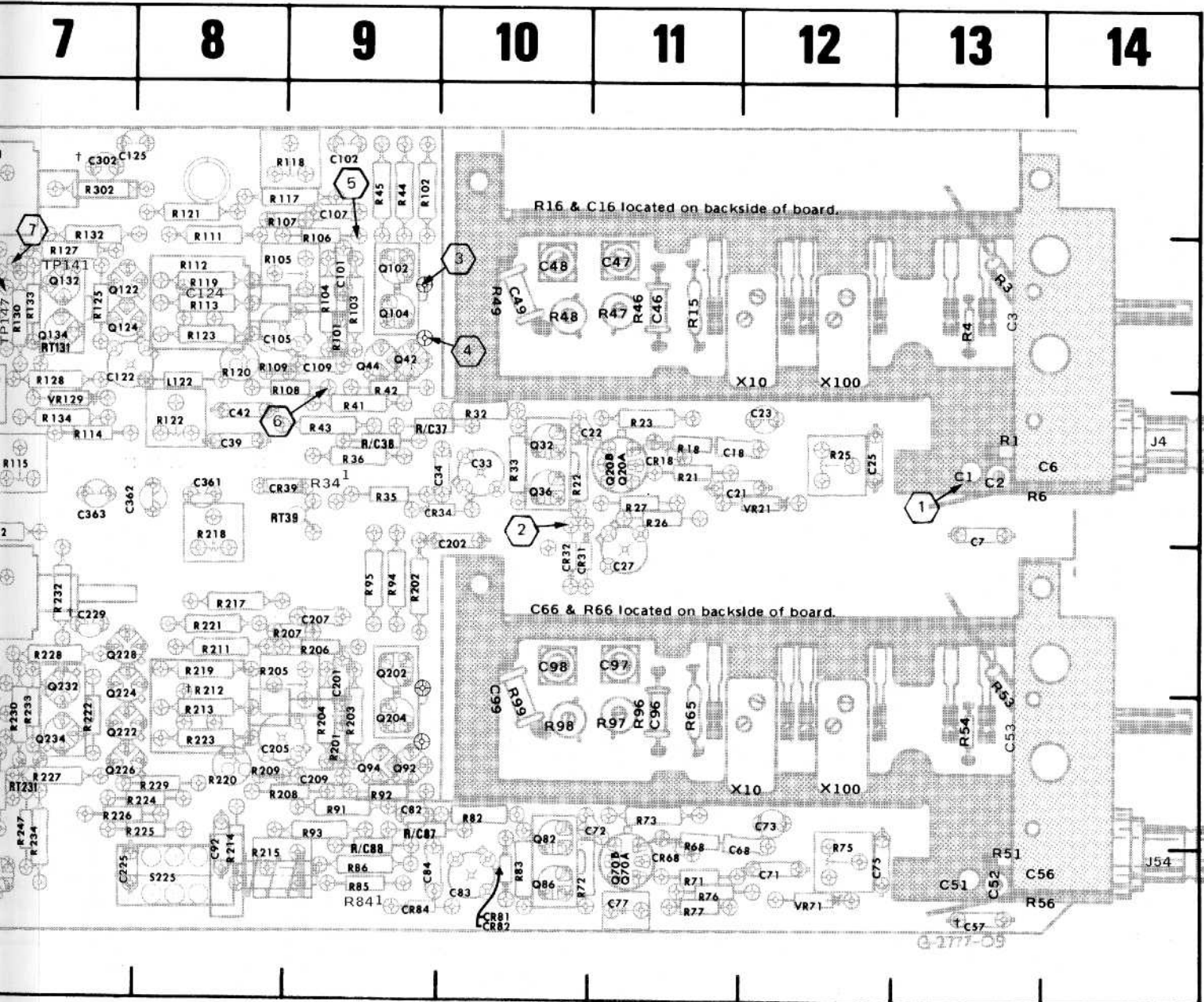






¹Not used with 670-3023 Vertical Output Board.

CKT NO	GRID LOC	CKT NO	GRID LOC	CKT NO	GRID LOC	CKT NO	GRID LOC	CKT NO	GRID LOC
C1	13C	C47	11B	C164	4B	L122	8B	Q164	4A
C2	13C	C48	10B	C165	4A	L149	6C	Q168	2A
C3	13B	C49	10B					Q304	5B
C6	13C	C101	9B	CR18	11C	Q20A	11C	Q308	6C
C7	13C	C102	9A	CR31	10D	Q20B	11C		
C18	11C	C105	8B	CR32	10D	Q32	10C	R1	13C
C21	11C	C107	9A	CR34	10C	Q36	10C	R3	13B
C22	11C	C109	9B	CR39	8C	Q42	9B	R4	13B
C23	12C	C122	7B	CR152	4B	Q44	9B	R6	13C
C25	12C	C124	8B	CR164	4A	Q102	9B	R15	11B
C27	11D	C125	7A	CR165	5A	Q104	9B	R18	11C
C33	10C	C135	6B	CR166	5A	Q122	7B	R21	11C
C34	10C	C137	6B	CR167	5A	Q124	7B	R22	10C
C36	10C	C142	6A			Q132	7B	R23	11C
C37	9C	C144	5A	J4	14C	Q134	7B	R25	12C
C38	9C	C149	6C	J162	2B	Q142	6A	R26	11C
C39	8C	C151	5B	J164	2A	Q148	6B	R27	11C
C42	8C	C161	3A	J168	1A	Q152	5B	R32	10C
C46	11B	C162	3B			Q162	4A	R33	10C
								R34 ¹	9C



+

A

B

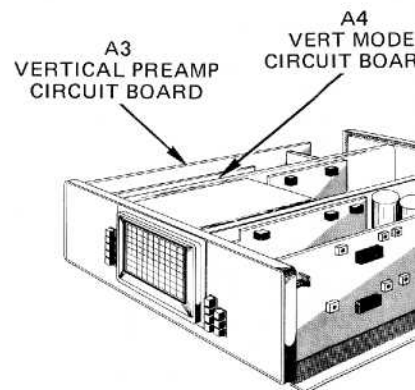
C

D

E

Attenuators and A3-Vertical Preamp circuit boards.

CKT NO	GRID LOC	CKT NO	GRID LOC	CKT NO	GRID LOC	CKT NO	GRID LOC	CKT NO	GRID LOC
Q164	4A	R35	9C	R106	9B	R130	7B	R155	5B
Q168	2A	R36	9C	R107	8A	R132	7B	R161	3B
Q304	5B	R37	9C	R108	8C	R133	7B	R162	3A
Q308	6C	R38	9C	R109	8B	R134	7C	R164	3A
		R41	9C	R111	8B	R135	6B	R165	4A
R1	13C	R42	9C	R112	8B	R136	6B	R168	3A
R3	13B	R43	9C	R113	8B	R137	6B	R169	3B
R4	13B	R44	9A	R114	7C	R138	6B		
R6	13C	R45	9A	R115	7C	R141	6B	RT39	9C
R15	11B	R46	11B	R116	7C	R142	5A	RT131	7B
R18	11C	R47	11B	R117	8A	R143	5A		
R21	11C	R48	10B	R119	8E	R144	6A		
R22	10C	R49	10B	R120	8B	R145	5A	VR21	12C
R23	11C			R121	8A	R146	5B	VR129	7C
R25	12C	R85	9F	R122	8C	R147	6B		
R26	11C	R101	9B	R123	8B	R149	6C		
R27	11C	R102	9A	R125	7B	R151	5B		
R32	10C	R103	9B	R127	7B	R152	4B		
R33	10C	R104	9E	R128	7B	R154	4B		
R34 ¹	9C	R105	8B						



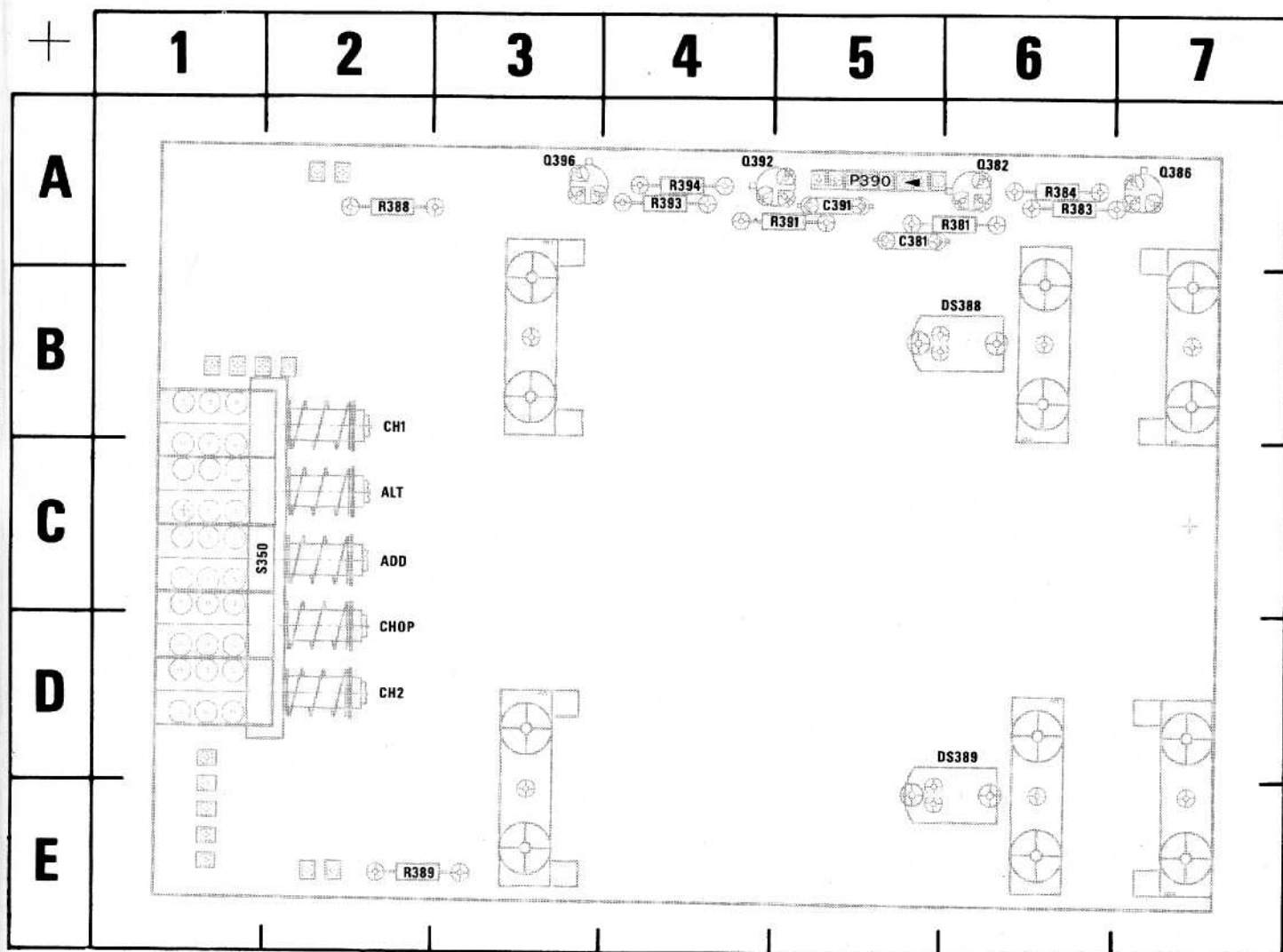
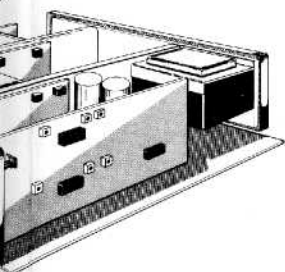


Fig. 8-3. A4-Vertical Mode Switch circuit board.

Located on back of board
R382

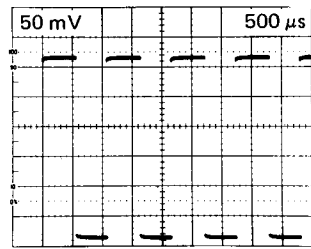
A4
VERT MODE
CIRCUIT BOARD



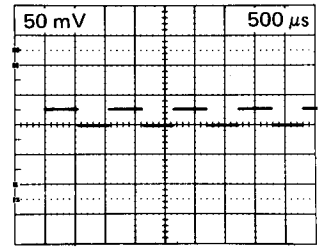
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C381	5A	R381	6A
C391	5A	R383	6A
		R384	6A
DS388	6B	R388	2A
DS389	6D	R389	2E
P390	5A	R391	5A
Q382	6A	R393	4A
Q386	7A	R394	4A
Q392	4A		
Q396	3A	S350	1C

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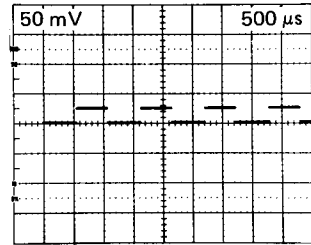
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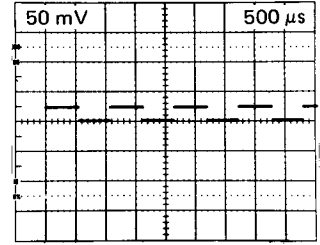
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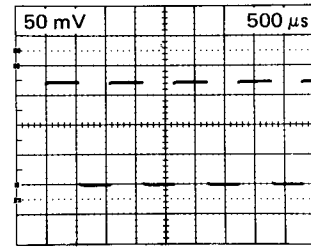
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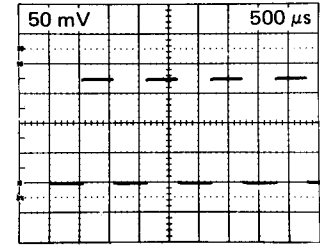
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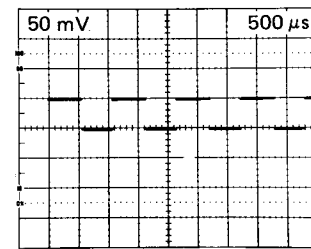
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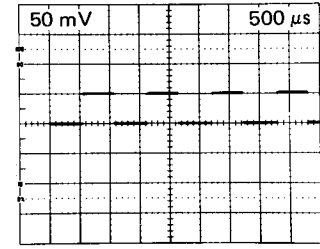
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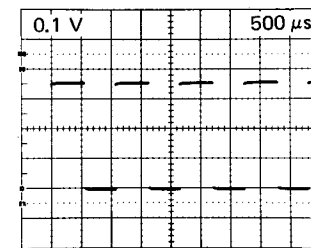
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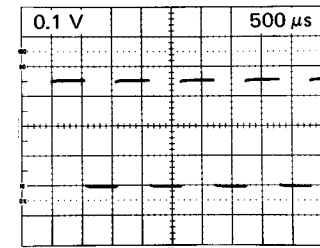
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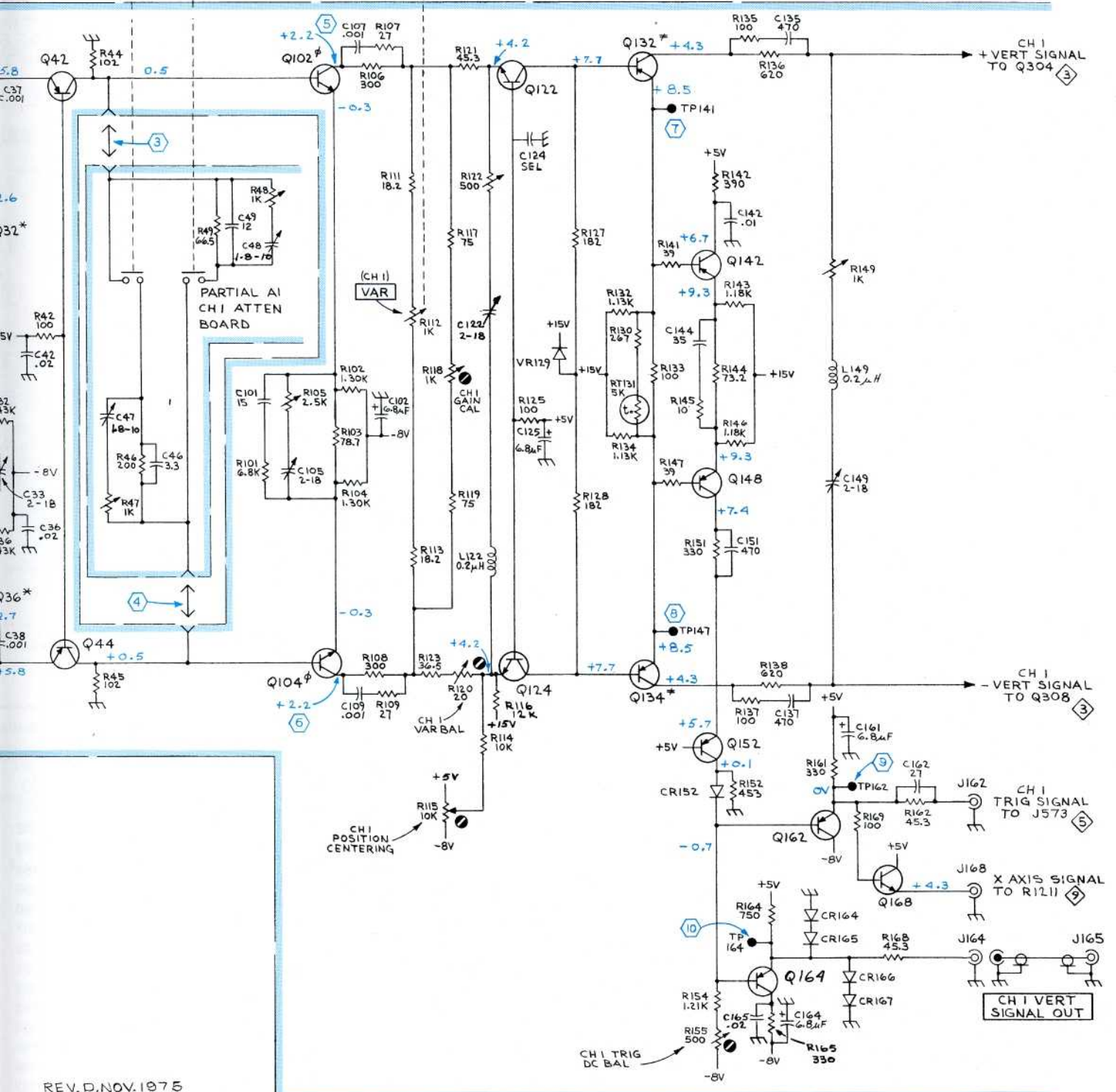
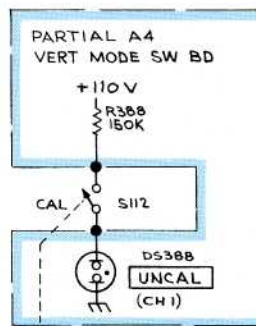
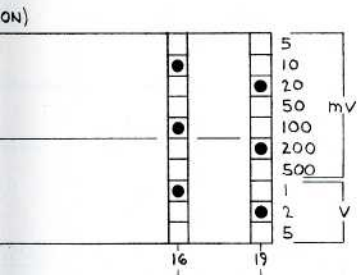


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CH 1 VERTICAL PREAMP ①

SN 8250000 and up

mgf 874

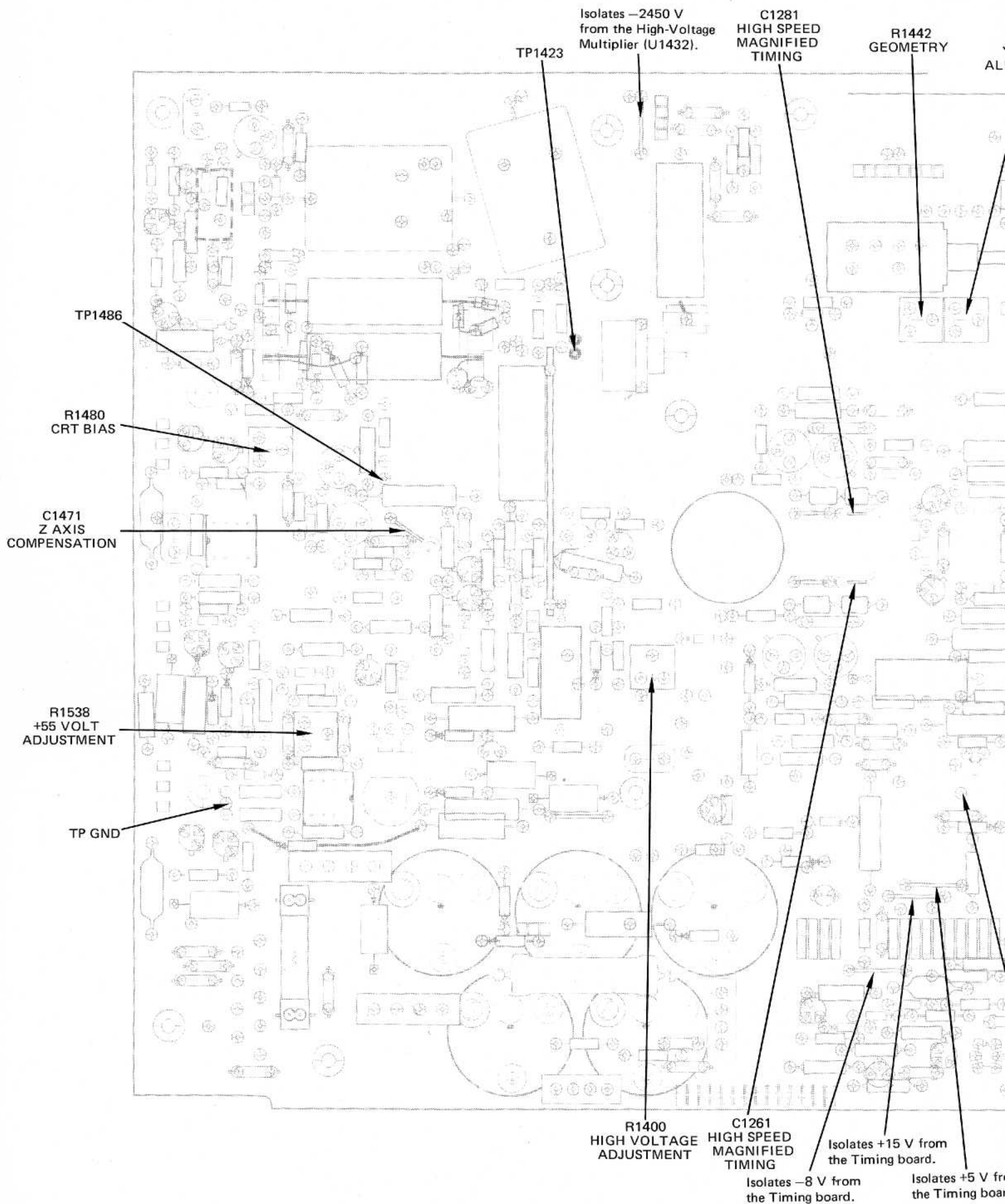
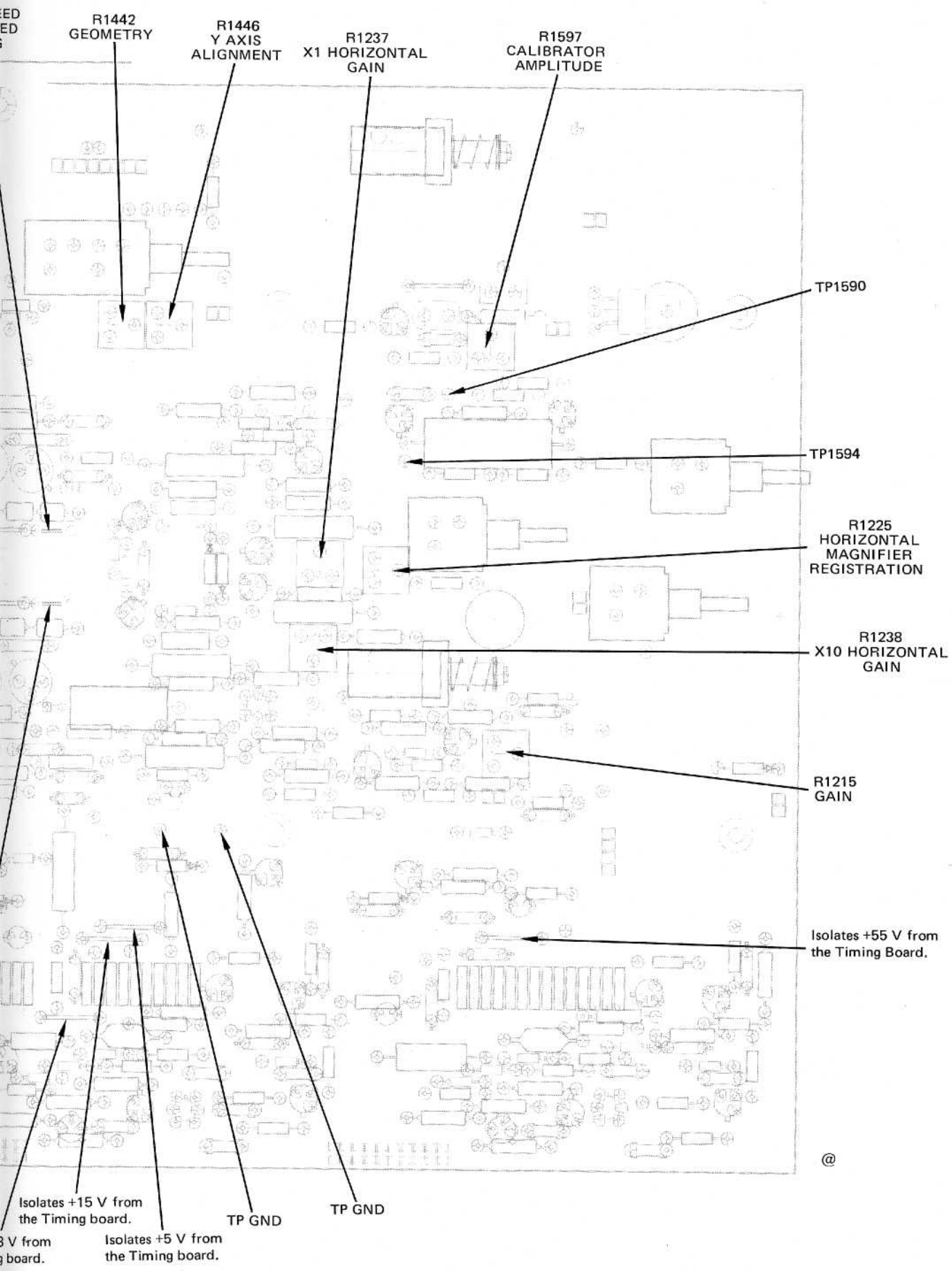
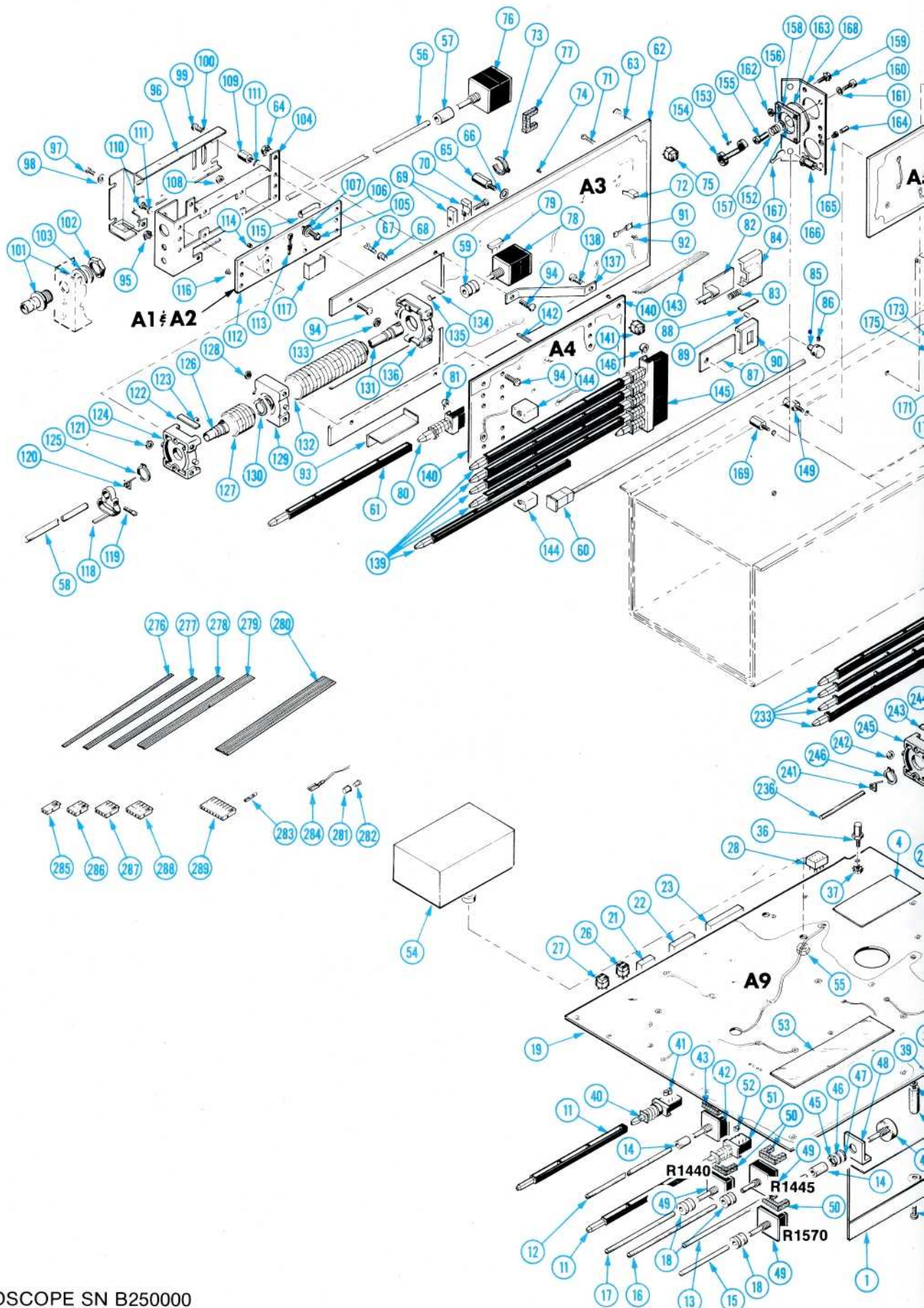


Fig. 8-19. Interface circuit board adjustment location.

ED
ED



@



465 OSCILLOSCOPE SN B250000

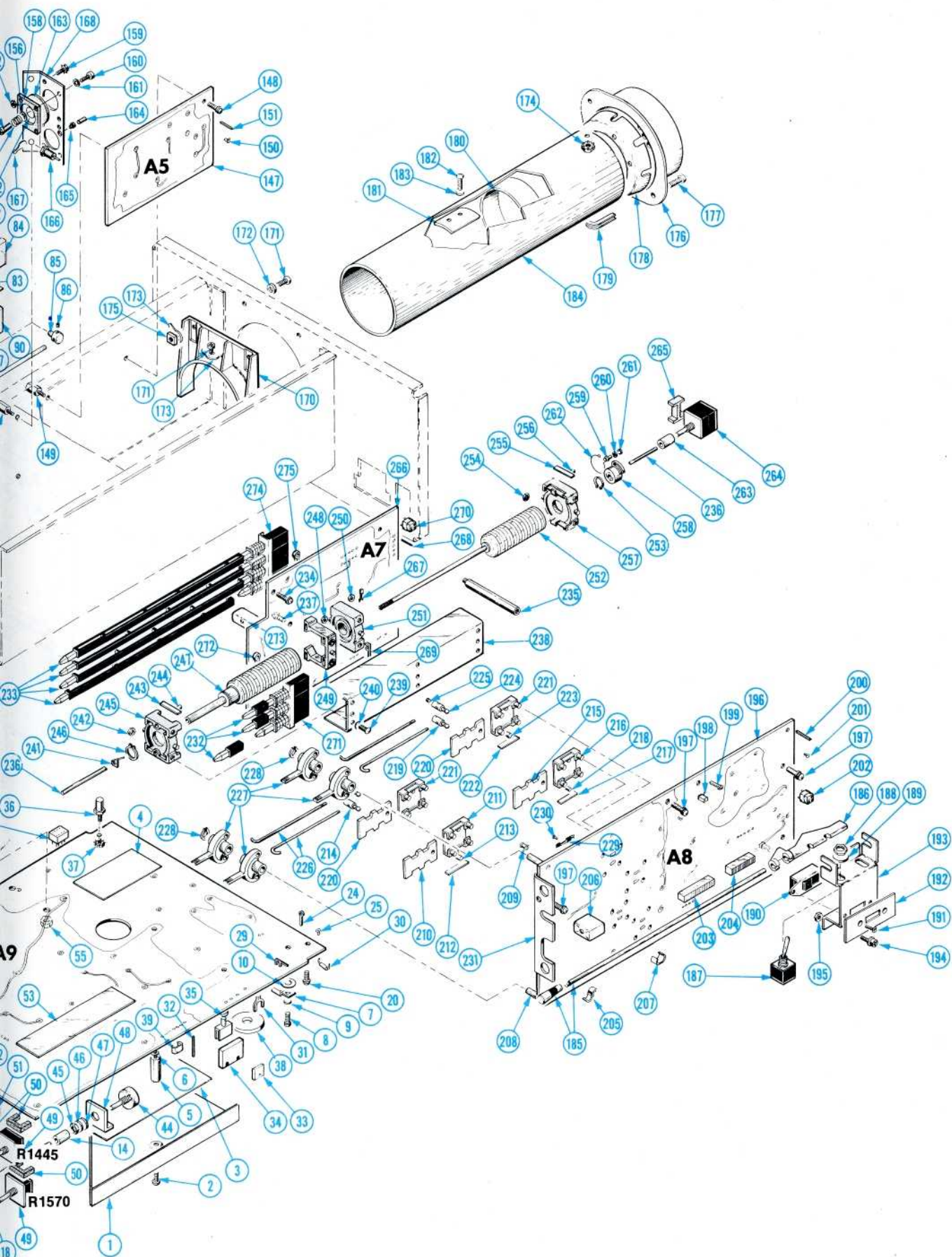


TABLE OF CONTENTS

BEFORE OPERATING	Page	BASIC OSCILLOSCOPE DISPLAYS (cont)	Page
INTRODUCTION	1	DELAYED SWEEP DISPLAY	17
SAFETY INFORMATION	1	MIXED SWEEP DISPLAY	18
OPERATING VOLTAGE	2	X-Y DISPLAY	18
OPTIONS	3	SINGLE SWEEP DISPLAY	19
CONTROLS, CONNECTORS AND INDICATORS		DM43/DM40 DISPLAYS AND MEASUREMENTS	
VERTICAL	4	RESISTANCE	20
DISPLAY	6	VOLTS	22
DM43/DM40	6	TEMPERATURE (DM43 ONLY)	24
TRIGGER	8	APPLICATIONS AND MEASUREMENTS	
HORIZONTAL, CALIBRATOR, AND POWER	12	PRELIMINARY	28
REAR PANEL	14	OPERATOR'S ADJUSTMENTS AND CHECKS	29
SIDE PANEL	15	PEAK-TO-PEAK VOLTAGE MEASUREMENTS —AC	31
BASIC OSCILLOSCOPE DISPLAYS		INSTANTANEOUS VOLTAGE MEASUREMENTS —DC	32
NORMAL SWEEP DISPLAY	16	ALGEBRAIC ADDITION	34
MAGNIFIED SWEEP DISPLAY	17		

REV. B, SEPT 1974

465 and DM43/DM40 Operators

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TABLE OF CONTENTS

BEFORE OPERATING	Page	BASIC OSCILLOSCOPE DISPLAYS (cont)	Page
INTRODUCTION	1	DELAYED SWEEP DISPLAY	17
SAFETY INFORMATION	1	MIXED SWEEP DISPLAY	18
OPERATING VOLTAGE	2	X-Y DISPLAY	18
OPTIONS	3	SINGLE SWEEP DISPLAY	19
CONTROLS, CONNECTORS AND INDICATORS		DM43/DM40 DISPLAYS AND MEASUREMENTS	
VERTICAL	4	RESISTANCE	20
DISPLAY	6	VOLTS	22
DM43/DM40	6	TEMPERATURE (DM43 ONLY)	24
TRIGGER	8	APPLICATIONS AND MEASUREMENTS	
HORIZONTAL, CALIBRATOR, AND POWER	12	PRELIMINARY	28
REAR PANEL	14	OPERATOR'S ADJUSTMENTS AND CHECKS	29
SIDE PANEL	15	PEAK-TO-PEAK VOLTAGE MEASUREMENTS —AC	31
BASIC OSCILLOSCOPE DISPLAYS		INSTANTANEOUS VOLTAGE MEASUREMENTS —DC	32
NORMAL SWEEP DISPLAY	16	ALGEBRAIC ADDITION	34
MAGNIFIED SWEEP DISPLAY	17		

REV. B, SEPT 1974

475 and DM43/DM40 Operators

i

TABLE OF CONTENTS (cont)

APPLICATIONS AND MEASUREMENTS (cont)	Page	APPLICATIONS AND MEASUREMENTS (cont)	Page
COMMON-MODE REJECTION	35	DM43/DM40 DELAYED OR MIXED SWEEP TIME MEASUREMENTS	48
AMPLITUDE COMPARISON MEASUREMENTS	36	Time Difference Between Repetitive Pulses (DM43/DM40)	48
TIME DURATION MEASUREMENTS	37	Time Duration (DM43/DM40)	49
FREQUENCY MEASUREMENTS	38	Frequency (DM43/DM40)	50
RISETIME MEASUREMENTS	39	Time Difference Between Two Pulses From Different Sources (DM43/DM40)	51
TIME-DIFFERENCE BETWEEN TWO PULSES FROM DIFFERENT SOURCES	40	Risetime (DM43/DM40)	52
TIME COMPARISON MEASUREMENTS	41	Mix (DM43/DM40)	53
BASIC 465 DELAYED OR MIXED SWEEP TIME MEASUREMENTS	42	DELAYED OR MIXED SWEEP MAGNIFICATION	53
Time Difference Between Repetitive Pulses (Basic 465)	42	Magnified Sweep Starts After Delay	53
Time Duration Measurements (Basic 465)	43	Triggered Delayed Sweep Magnification	55
Frequency (Basic 465)	44	PHASE DIFFERENCE MEASUREMENTS	56
Time Difference Between Two Pulses From Different Sources (Basic 465)	45	HIGH RESOLUTION PHASE DIFFERENCE MEASUREMENTS	57
Risetime (Basic 465)	47	PULSE JITTER MEASUREMENTS	58
Mix (Basic 465)	48		

TABLE OF CONTENTS (cont)

APPLICATIONS AND MEASUREMENTS (cont)	Page	APPLICATIONS AND MEASUREMENTS (cont)	Page
COMMON-MODE REJECTION	35	DM43/DM40 DELAYED OR MIXED SWEEP TIME MEASUREMENTS	48
AMPLITUDE COMPARISON MEASUREMENTS	36	Time Difference Between Repetitive Pulses (DM43/DM40)	48
TIME DURATION MEASUREMENTS	37	Time Duration (DM43/DM40)	49
FREQUENCY MEASUREMENTS	38	Frequency (DM43/DM40)	50
RISETIME MEASUREMENTS	39	Time Difference Between Two Pulses From Different Sources (DM43/DM40)	51
TIME-DIFFERENCE BETWEEN TWO PULSES FROM DIFFERENT SOURCES	40	Risetime (DM43/DM40)	52
TIME COMPARISON MEASUREMENTS	41	Mix (DM43/DM40)	53
BASIC 475 DELAYED OR MIXED SWEEP TIME MEASUREMENTS	42	DELAYED OR MIXED SWEEP MAGNIFICATION	53
Time Difference Between Repetitive Pulses (Basic 475)	42	Magnified Sweep Starts After Delay	53
Time Duration Measurements (Basic 475)	43	Triggered Delayed Sweep Magnification	55
Frequency (Basic 475)	44	PHASE DIFFERENCE MEASUREMENTS	56
Time Difference Between Two Pulses From Different Sources (Basic 475)	45	HIGH RESOLUTION PHASE DIFFERENCE MEASUREMENTS	57
Risetime (Basic 475)	47	PULSE JITTER MEASUREMENTS	58
Mix (Basic 475)	48		

TABLE OF CONTENTS (cont)

OPERATOR'S SPECIFICATIONS	Page	OPERATOR'S SPECIFICATIONS (cont)	Page
VERTICAL	59	TEMPERATURE—DM43 ONLY, WITH PROBE	63
TRIGGERING	60	DC VOLTAGE DM43/DM40	63
DIFFERENTIAL TIME MEASUREMENT (BASIC 465)	60	AC POWER SOURCE	64
DIFFERENTIAL TIME MEASUREMENT (DM43/DM40)	61	ENVIRONMENTAL	64
HORIZONTAL	61	ACCESSORIES	
CALIBRATOR	61	STANDARD ACCESSORIES INCLUDED	65
Z-AXIS INPUT	62	OPTIONAL ACCESSORIES	65
OUTPUTS	62	OPTIONS	
RESISTANCE DM43/DM40	62	OPTION 4	66
TIME DM43/DM40	62	OPTION 7	66

REV. B, SEPT 1974

465 and DM43/DM40 Operators

iii

TABLE OF CONTENTS (cont)

OPERATOR'S SPECIFICATIONS	Page	OPERATOR'S SPECIFICATIONS (cont)	Page
VERTICAL	59	TEMPERATURE—DM43 ONLY, WITH PROBE	63
TRIGGERING	60	DC VOLTAGE DM43/DM40	63
DIFFERENTIAL TIME MEASUREMENT (BASIC 475)	60	AC POWER SOURCE	64
DIFFERENTIAL TIME MEASUREMENT (DM43/DM40)	61	ENVIRONMENTAL	64
HORIZONTAL	61	ACCESSORIES	
CALIBRATOR	61	STANDARD ACCESSORIES INCLUDED	65
Z-AXIS INPUT	62	OPTIONAL ACCESSORIES	65
OUTPUTS	62	OPTIONS	
RESISTANCE DM43/DM40	62	OPTION 4	66
TIME DM43/DM40	62	OPTION 7	66

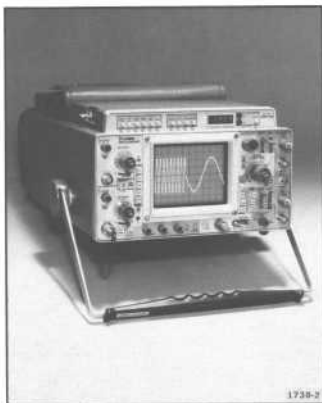
REV. B, SEPT 1974

475 and DM43/DM40 Operators

iii



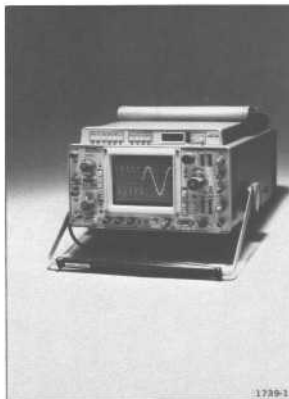
Basic 465 Oscilloscope.



465 Oscilloscope with DM 43 digital multimeter.

465 and DM43/DM40 Operators

REV. B, SEPT 1974



475 Oscilloscope with DM 43 digital multimeter.



Basic 475 Oscilloscope.

475 and DM43/DM40 Operators

REV. C, JAN. 1975

BEFORE OPERATING

INTRODUCTION

The Tektronix 465 Oscilloscope is a dual-channel, portable instrument. The dual-channel dc-to-100 MHz vertical system provides calibrated deflection factors from 5 millivolts to 5 volts/division. The sweep trigger circuits are capable of stable triggering over the full bandwidth capabilities of the vertical deflection system. The horizontal deflection system provides calibrated sweep rates from 0.5 second to 0.05 microsecond/division along with delayed sweep features for accurate relative-time measurements. A X10 magnifier extends the calibrated sweep rate to 5 nanoseconds/division. The instrument operates over a wide variation of line voltages and frequencies. Maximum power consumption is about 100 watts.

The Tektronix DM43 Digital Multimeter measures 0 ohms to 20 megohms, 0 dc volts to 1200 dc volts (+ or -) or -55°C to +150°C and displays the measurement on a digital display while the oscilloscope operates normally.

The digital multimeter and oscilloscope combine to provide a digital readout of the time between any two points on the oscilloscope display.

REV. B, SEPT 1974

465 and DM43/DM40 Operators

1

The DM40 is identical to the DM43, except that the DM40 lacks temperature measurement capability.

SAFETY INFORMATION

The instrument is designed to operate from a single-phase power source with one of the current-carrying conductors (the Neutral Conductor) at ground (earth) potential. Operation from power sources where both current-carrying conductors are live with respect to ground (such as phase-to-phase on a three-wire system) is not recommended, since only the Line Conductor has over-current (fuse) protection within the instrument.

The instrument has a three-wire power cord with a three-terminal polarized plug for connection to the power source and safety-earth. The ground (earth) terminal of the plug is directly connected to the instrument frame. For electric-shock protection, insert this plug only in a mating outlet with a safety-earth contact.

BEFORE OPERATING

INTRODUCTION

The Tektronix 475 Oscilloscope is a dual-channel, portable instrument. The dual-channel dc-to-200 MHz vertical system provides calibrated deflection factors from 2 millivolts to 5 volts/division. The sweep trigger circuits are capable of stable triggering over the full bandwidth capabilities of the vertical deflection system. The horizontal deflection system provides calibrated sweep rates from 0.5 second to 0.01 microsecond/division along with delayed sweep features for accurate relative-time measurements. A X10 magnifier extends the calibrated sweep rate to 1 nanosecond/division. The instrument operates over a wide variation of line voltages and frequencies. Maximum power consumption is about 100 watts.

The Tektronix DM43 Digital Multimeter measures 0 ohms to 20 megohms, 0 dc volts to 1200 dc volts (+ or -) or -55°C to +150°C and displays the measurement on a digital display while the oscilloscope operates normally.

The digital multimeter and oscilloscope combine to provide a digital readout of the time between any two points on the oscilloscope display.

REV. B, SEPT 1974

475 and DM43/DM40 Operators

1

The DM40 is identical to the DM43, except that the DM40 lacks temperature measurement capability.

SAFETY INFORMATION

The instrument is designed to operate from a single-phase power source with one of the current-carrying conductors (the Neutral Conductor) at ground (earth) potential. Operation from power sources where both current-carrying conductors are live with respect to ground (such as phase-to-phase on a three-wire system) is not recommended, since only the Line Conductor has over-current (fuse) protection within the instrument.

The instrument has a three-wire power cord with a three-terminal polarized plug for connection to the power source and safety-earth. The ground (earth) terminal of the plug is directly connected to the instrument frame. For electric-shock protection, insert this plug only in a mating outlet with a safety-earth contact.

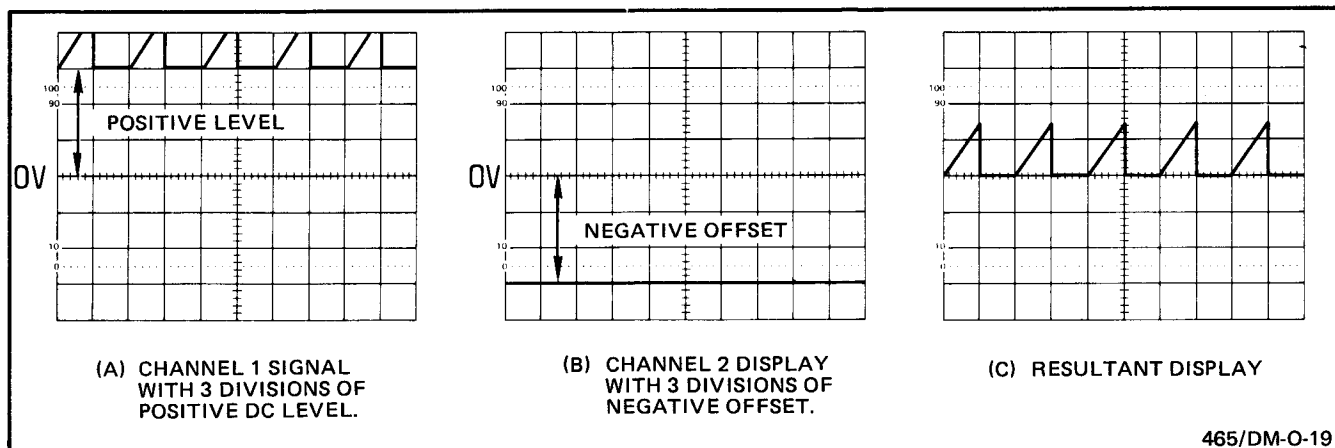


Fig. 16. Algebraic addition.

COMMON-MODE REJECTION

The ADD mode can be used to display signals that contain undesirable components. These undesirable components can be eliminated through common mode rejection. The precautions given under algebraic addition should be observed.

EXAMPLE: The signal applied to the CH 1 input contains unwanted line frequency components (see Fig. 17A.). To remove the undesired components use the following procedure.

1. Connect a line frequency signal to the CH 2 input.
2. Set the VERT MODE switch to ALT and the CH 2 INVERT switch to on (button in). Adjust the CH 2

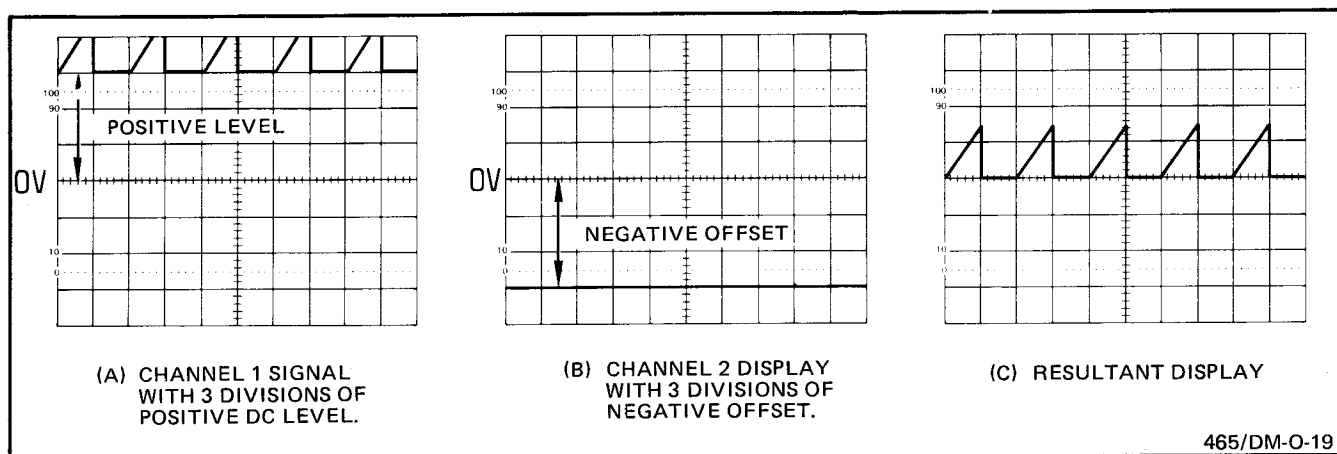


Fig. 16. Algebraic addition.

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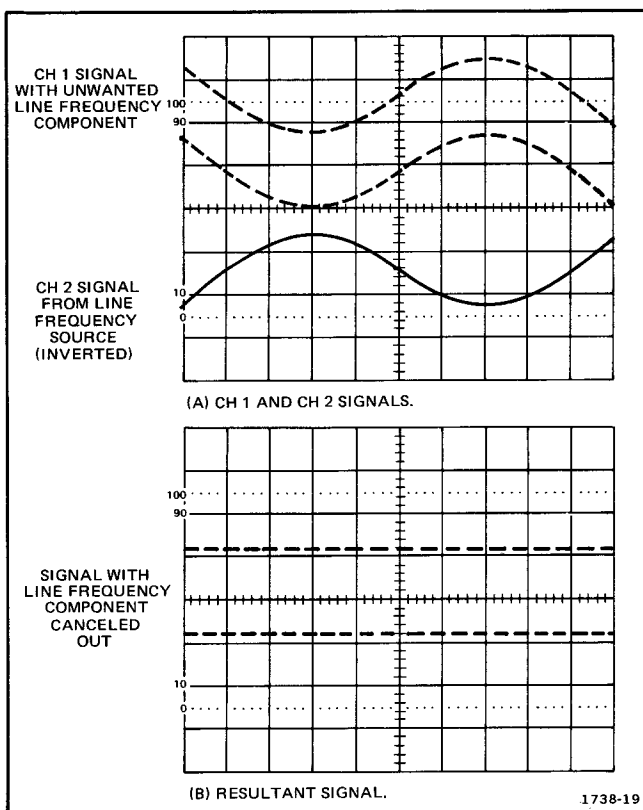


Fig. 17. Common-mode rejection.

VOLTS/DIV and VAR VOLTS/DIV controls so the CH 2 display is about the same amplitude as the undesired portion of the CH 1 display (see Fig. 17A).

3. Set the VERT MODE switch to ADD. Slightly readjust the CH 2 VAR VOLTS/DIV control for maximum cancellation of the undesired signal component (see Fig. 17B).

AMPLITUDE COMPARISON MEASUREMENTS

If comparisons of an unknown signal with a reference signal are repetitious (e.g., on an assembly line test) it is possible to obtain more accurate easily read measurements if the VAR VOLTS/DIV control is adjusted to set the reference signal to an exact number of divisions. The unknown signal can then be quickly and easily compared with or adjusted to an exact number of divisions.

Other unknown signals may be measured without disturbing the setting of the VAR VOLTS/DIV control by establishing a vertical conversion factor and an arbitrary deflection factor. The amplitude of the reference signal must be known before a vertical conversion factor can be established.

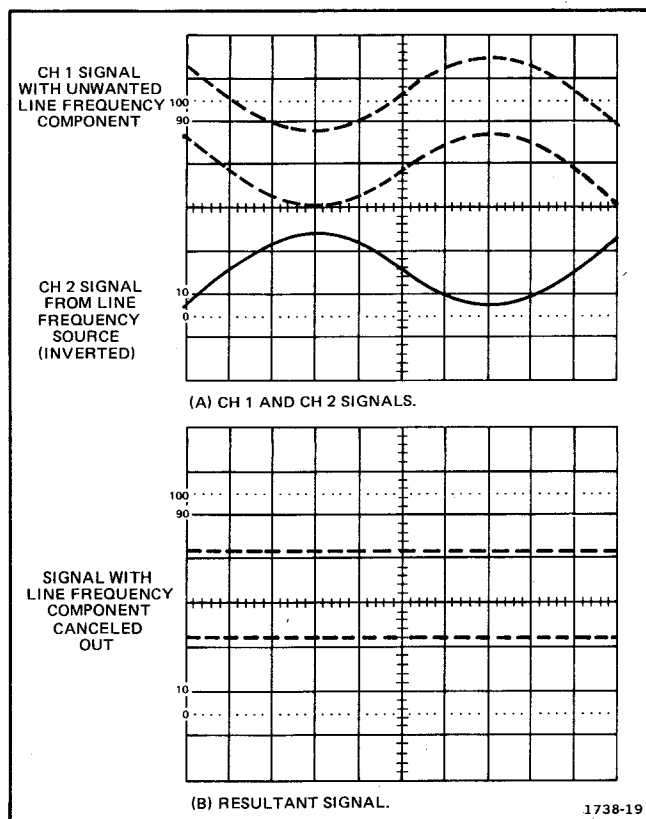


Fig. 17. Common-mode rejection.

VOLTS/DIV and VAR VOLTS/DIV controls so the CH 2 display is about the same amplitude as the undesired portion of the CH 1 display (see Fig. 17A).

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Other unknown signals may be measured without disturbing the setting of the VAR VOLTS/DIV control by establishing a vertical conversion factor and an arbitrary deflection factor. The amplitude of the reference signal must be known before a vertical conversion factor can be established.

EXAMPLE: The apparent magnification of a display with an A TIME/DIV switch setting of .1 ms and a B TIME/DIV switch setting of 1 μ s is:

$$\text{Apparent Magnification (Delayed Sweep)} = \frac{\text{A TIME/DIV setting}}{\text{B TIME/DIV setting}}$$

Substituting the given values:

$$\text{Apparent Magnification} = \frac{1 \times 10^{-4}}{1 \times 10^{-6}}$$

The apparent magnification is 100 times.

Triggered Delayed Sweep Magnification

The delayed sweep magnification method just described may produce too much jitter at high apparent magnification ranges. Operating the B Sweep in a triggered mode provides a more stable display since the delayed display is triggered at the same point each time.

1. Set up the display as given in steps 1 through 6 under "Magnified Sweep Starts After Delay".

2. Set the B Trigger SOURCE switch to the same position as the A Trigger SOURCE switch.

3. Adjust the B LEVEL control so the intensified zone on the trace is stable. (If an intensified zone cannot be obtained, see step 4.)

4. Inability to intensify the desired portion indicates that the signal does not meet the triggering requirements. If the condition cannot be remedied with the B Triggering controls or by increasing the display amplitude (lower VOLTS/DIV setting), trigger B Sweep externally.

5. When the correct portion is intensified, set the HORIZ DISPLAY switch to B DLY'D. Slight readjustment of the B LEVEL control may be necessary for a stable display.

6. Measurements are made and magnification factors are calculated as in the STARTS AFTER DELAY mode previously given.

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465 and DM43/DM40 Operators

55

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6. Measurements are made and magnification factors are calculated as in the STARTS AFTER DELAY mode previously given.

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475 and DM43/DM40 Operators

55

PHASE DIFFERENCE MEASUREMENTS

Use either the CHOP or ALT mode. Set the A Trigger SOURCE switch to CH 1. The reference signal should precede the comparison signal in time. Use coaxial cables or probes that have equal time delay to connect the signals to the input connectors.

If the signals are of opposite polarity, set the INVERT pushbutton to invert the Channel 2 display (signals may be of opposite polarity due to 180° phase difference; if so, take this into account in the final calculation). Set the CH 1 and CH 2 VOLTS/DIV switches and the CH 1 and CH 2 VAR controls so the displays are equal in amplitude.

Set the TIME/DIV switch for about a one-cycle waveform. Position the display and turn the A VAR TIME/DIV control for 1 reference signal cycle in exactly eight divisions (see Fig. 30). Each division of the graticule represents 45° of the cycle ($360^\circ \div 8 \text{ divisions} = 45^\circ/\text{division}$). The sweep rate can be stated in terms of degrees as 45°/division.

Measure the horizontal difference between corresponding points on the waveforms and multiply the distance measured (in divisions) by 45°/division (sweep rate) to obtain the amount of phase difference.

56

465 and DM43/DM40 Operators

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56

475 and DM43/DM40 Operators

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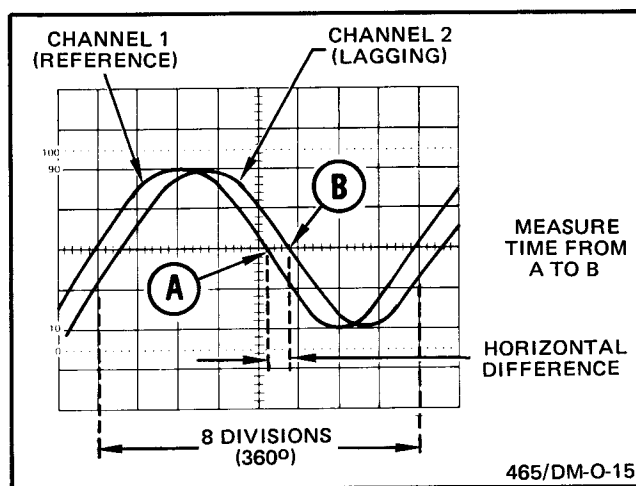


Fig. 30. Phase difference.

EXAMPLE: The horizontal difference is 0.6 division with a sweep rate of 45°/division as shown in Fig. 30.

Using the formula:

$$\text{Phase Difference} = \text{horizontal difference divisions} \times \text{sweep (degrees/div)}$$

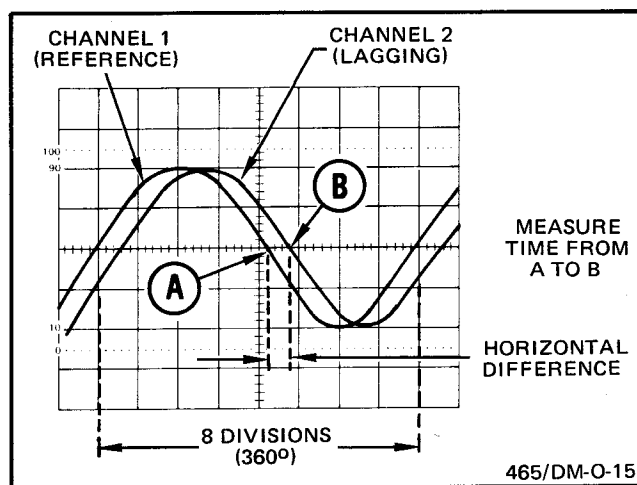


Fig. 30. Phase difference.

EXAMPLE: The horizontal difference is 0.6 division with a sweep rate of 45°/division as shown in Fig. 30.

Using the formula:

$$\text{Phase Difference} = \text{horizontal difference divisions} \times \text{sweep (degrees/div)}$$

Substituting the given values:

$$\text{Phase Difference} = 0.6 \times 45^\circ = 27^\circ.$$

HIGH RESOLUTION PHASE DIFFERENCE MEASUREMENTS

Make more accurate phase measurements by increasing the sweep rate (without changing the A VAR TIME/DIV control) by using the X10 MAG mode. Delayed sweep magnification may also be used (see Fig. 31).

EXAMPLE: If the sweep rate were increased 10 times with the magnifier, the magnified sweep rate would be $45^\circ \div 10 = 4.5^\circ/\text{division}$. Fig. 31 shows the same signals as used in Fig. 30 but with the X10 MAG switch set to X10. With a horizontal difference of 6 divisions, the phase difference is:

$$\text{Phase Difference} = \text{horizontal difference (divisions)} \times \text{magnified sweep rate (degrees/div)}$$

Substituting the given values:

$$\text{Phase Difference} = 6 \times 4.5^\circ = 27^\circ.$$

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465 and DM43/DM40 Operators

57

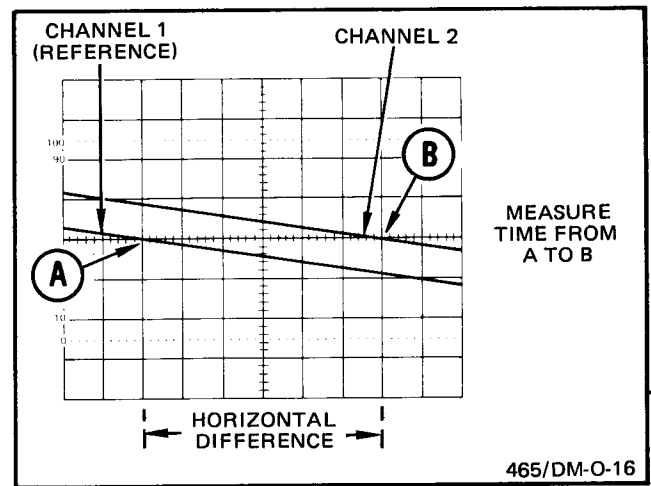


Fig. 31. High resolution phase difference.

Substituting the given values:

$$\text{Phase Difference} = 0.6 \times 45^\circ = 27^\circ.$$

HIGH RESOLUTION PHASE DIFFERENCE MEASUREMENTS

Make more accurate phase measurements by increasing the sweep rate (without changing the A VAR TIME/DIV control) by using the X10 MAG mode. Delayed sweep magnification may also be used (see Fig. 31).

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$$\text{Phase Difference} = \text{horizontal difference (divisions)} \times \text{magnified sweep rate (degrees/div)}$$

Substituting the given values:

$$\text{Phase Difference} = 6 \times 4.5^\circ = 27^\circ.$$

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475 and DM43/DM40 Operators

57

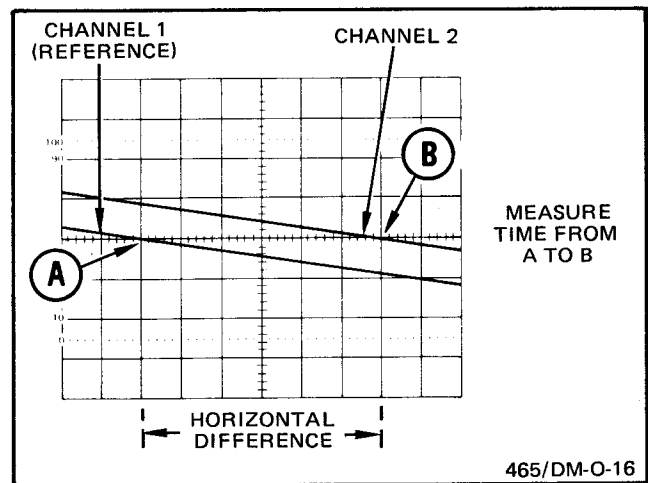


Fig. 31. High resolution phase difference.

PULSE JITTER MEASUREMENTS

Be sure the VAR TIME/DIV switch is in the calibrated detent. Set the B TIME/DIV switch to intensify the full rising portion of the pulse. Set the HORIZ DISPLAY switch to B DLY'D.

Pulse jitter is shown by horizontal movement of the pulse and includes the inherent jitter of the Delayed Sweep (see Fig. 32). Multiply the distance by the B TIME/DIV switch setting to obtain pulse jitter time.

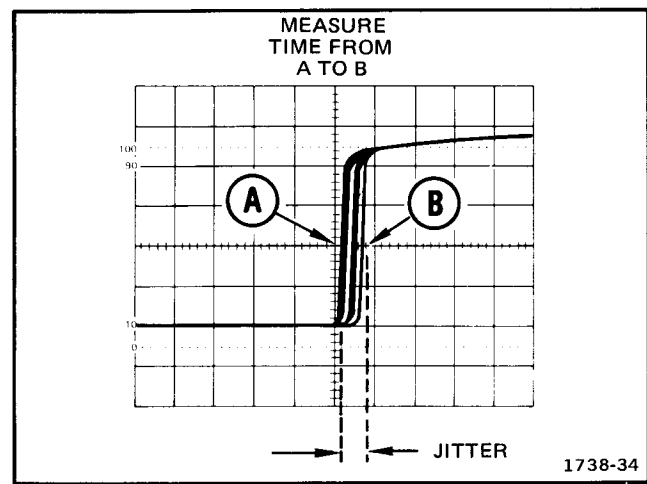


Fig. 32. Pulse jitter.

PULSE JITTER MEASUREMENTS

Be sure the VAR TIME/DIV switch is in the calibrated detent. Set the B TIME/DIV switch to intensify the full rising portion of the pulse. Set the HORIZ DISPLAY switch to B DLY'D.

Pulse jitter is shown by horizontal movement of the pulse and includes the inherent jitter of the Delayed Sweep (see Fig. 32). Multiply the distance by the B TIME/DIV switch setting to obtain pulse jitter time.

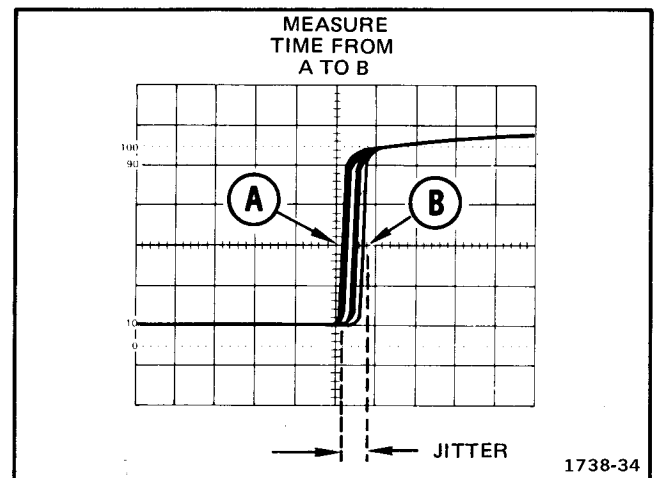


Fig. 32. Pulse jitter.